

混合信号微控制器

特性

- 低电源电压范围: **1.8 V 至 3.6 V**
- 超低功耗
 - 运行模式: **220 μ A** (在 **1MHz** 频率和 **2.2V** 电压条件下)
 - 待机模式: **0.5 μ A**
 - 关断模式 (RAM 保持): **0.1 μ A**
- **5** 种节能模式
- 可在不到 **1 μ s** 的时间里超快速地从待机模式唤醒
- **16** 位 **RISC** 架构, 高达 **12-MHz** 系统时钟
- 基本时钟模块配置
 - 高达 **12 MHz** 的内部频率, 具有 **2** 种校准频率
 - 内部超低功耗低频 (**LF**) 振荡器
 - 高达 **16 MHz** 的高频(**HF**) 晶体
 - 谐振器
 - 外部数字时钟信号源
- 多达 **3** 个具有差分 **PGA** 输入的 **24** 位 $\Sigma\Delta$ 模数 (**A/D**) 转换器
- 具有 **3** 个捕获/比较寄存器的 **16** 位 **Timer_A**
- 串行通信接口 (**USART**), 利用软件来选择异步 **UART** 或同步 **SPI**
- **16** 位硬件乘法器
- 欠压检测器
- 具有可编程电平检测功能的电源电压监控器/监视器
- 串行板上编程, 无需从外部进行电压编程, 利用安全熔丝 (**Security Fuse**) 实现可编程代码保护
- 片上仿真模块
- 系列成员汇总于 [表 1](#).
- 如需了解完整的模块说明, 请查阅 **MSP430x2xx** 系列用户指南, 文献编号 [SLAU144](#)

说明

德州仪器 **MSP430™** 系列超低功耗微控制器包含多种器件, 它们具有面向各种应用的不同外设集。这种架构与 5 种低功耗模式相组合, 专为在便携式测量应用中延长电池的使用寿命而优化。该器件具有一个强大的 **16** 位 **RISC** **CPU**、**16** 位寄存器和有助于获得最大编码效率的常数发生器。数字控制振荡器 (**DCO**) 可在不到 **1 μ s** 的时间里完成从低功耗模式至运行模式的唤醒。

MSP430AFE2x3 器件是超低功耗混合信号微控制器, 集成了三个独立的 **24** 位 $\Sigma\Delta$ **A/D** 转换器、一个 **16** 位定时器、一个 **16** 位硬件乘法器、**USART** 通信接口、看门狗定时器和 **11** 个 **I/O** 引脚。

MSP430AFE2x2 器件与 **MSP430AFE2x3** 基本相同, 唯一的差异是前者仅集成了两个 **24** 位 $\Sigma\Delta$ **A/D** 转换器。

MSP430AFE2x1 器件与 **MSP430AFE2x3** 基本相同, 唯一的差异是前者仅集成了一个 **24** 位 $\Sigma\Delta$ **A/D** 转换器。

可提供的系列成员汇总于 [表 1](#)。



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表 1. 系列成员⁽¹⁾

设备	闪存 (KB)	SRAM (字节)	EEM	SD24_A 转换器	16 位乘法器	Timer_A ⁽²⁾	USART (UART/SPI)	时钟	I/O	封装类型 ⁽³⁾
MSP430AFE253IPW	16	512	1	3	1	3	1	HF, DCO, VLO	11	24 引脚 TSSOP 封装
MSP430AFE233IPW	8	512	1	3	1	3	1	HF, DCO, VLO	11	24 引脚 TSSOP 封装
MSP430AFE223IPW	4	256	1	3	1	3	1	HF, DCO, VLO	11	24 引脚 TSSOP 封装
MSP430AFE252IPW	16	512	1	2	1	3	1	HF, DCO, VLO	11	24 引脚 TSSOP 封装
MSP430AFE232IPW	8	512	1	2	1	3	1	HF, DCO, VLO	11	24 引脚 TSSOP 封装
MSP430AFE222IPW	4	256	1	2	1	3	1	HF, DCO, VLO	11	24 引脚 TSSOP 封装
MSP430AFE251IPW	16	512	1	1	1	3	1	HF, DCO, VLO	11	24 引脚 TSSOP 封装
MSP430AFE231IPW	8	512	1	1	1	3	1	HF, DCO, VLO	11	24 引脚 TSSOP 封装
MSP430AFE221IPW	4	256	1	1	1	3	1	HF, DCO, VLO	11	24 引脚 TSSOP 封装

(1) 有关最新的封装和订购信息，请参阅本文档结尾的“封装选项附录”，或访问 TI 网站：www.ti.com。

(2) 序列中的每个数代表 Timer_A 的一个例示，并反映出其可使用的捕获/比较寄存器及 PWM 输出发生器的相关数量。例如：一个 (3, 5) 数列将代表 Timer_A 的两个例示，第一个例示和第二个例示分别具有 3 个和 5 个捕获/比较寄存器和 PWM 输出发生器。

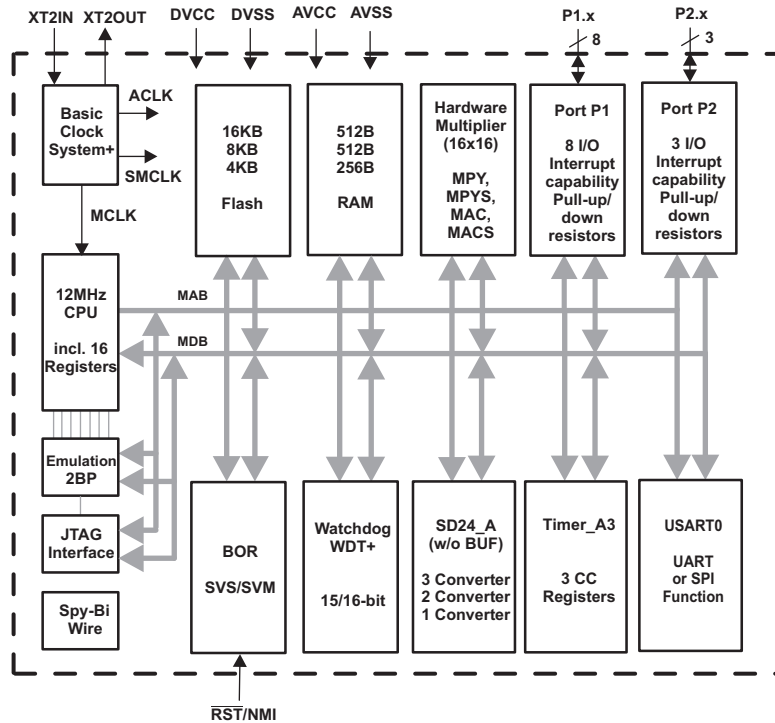
(3) 封装图样、热数据和符号可登录 www.ti.com/packaging 获取。

Development Tool Support

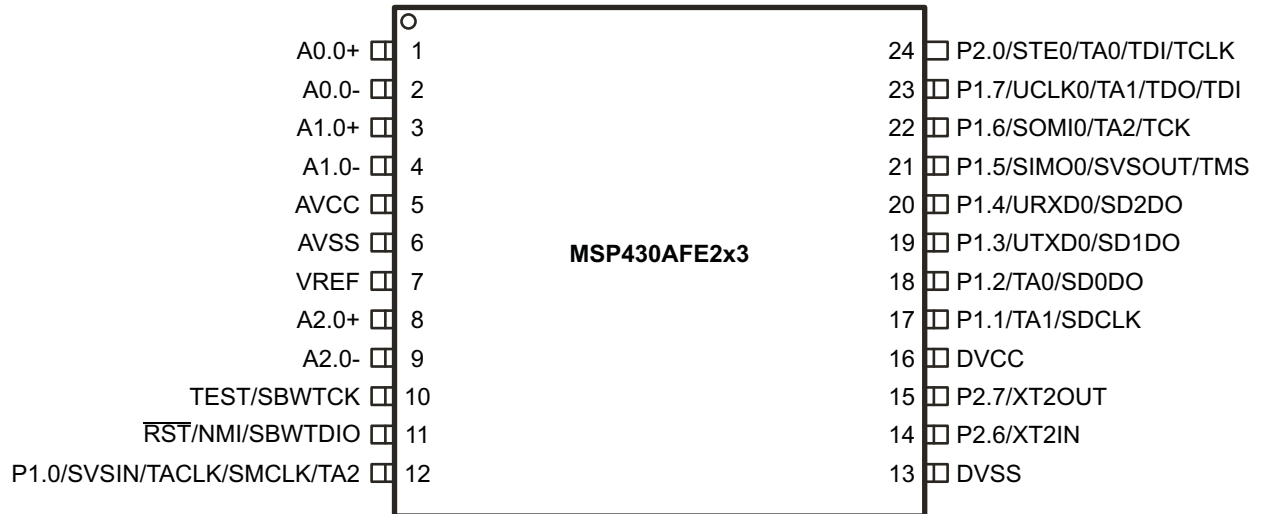
All MSP430™ microcontrollers include an Embedded Emulation Module (EEM) that allows advanced debugging and programming through easy-to-use development tools. Recommended hardware options include:

- Debugging and Programming Interface
 - MSP-FET430UIF (USB)
 - MSP-FET430PIF (Parallel Port)
- Debugging and Programming Interface with Target Board
 - MSP-TS430PW24
- Production Programmer
 - MSP-GANG430

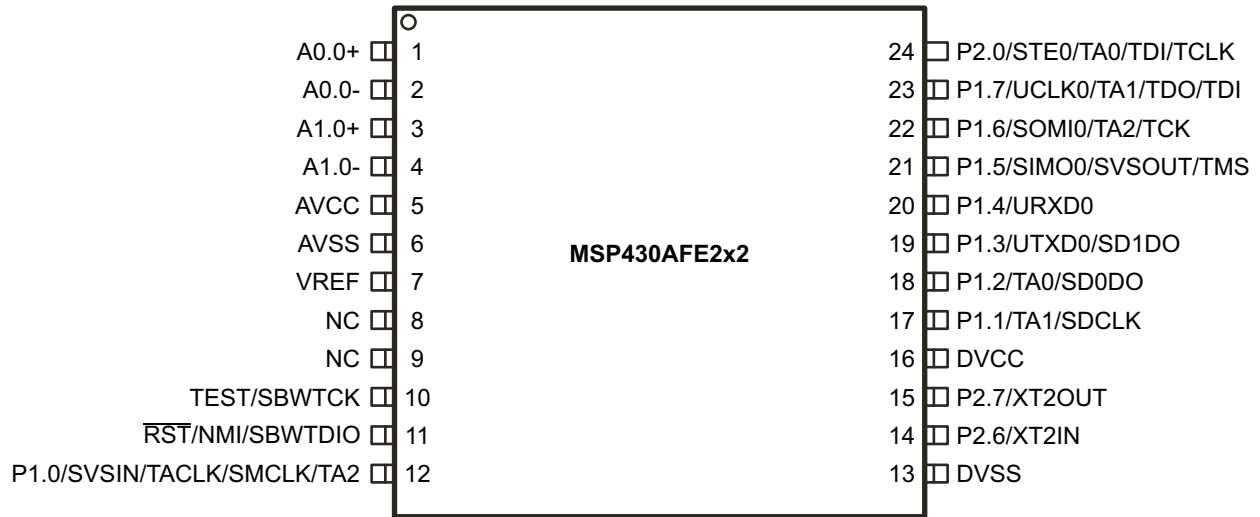
Functional Block Diagram



Pin Designation, MSP430AFE2x3IPW

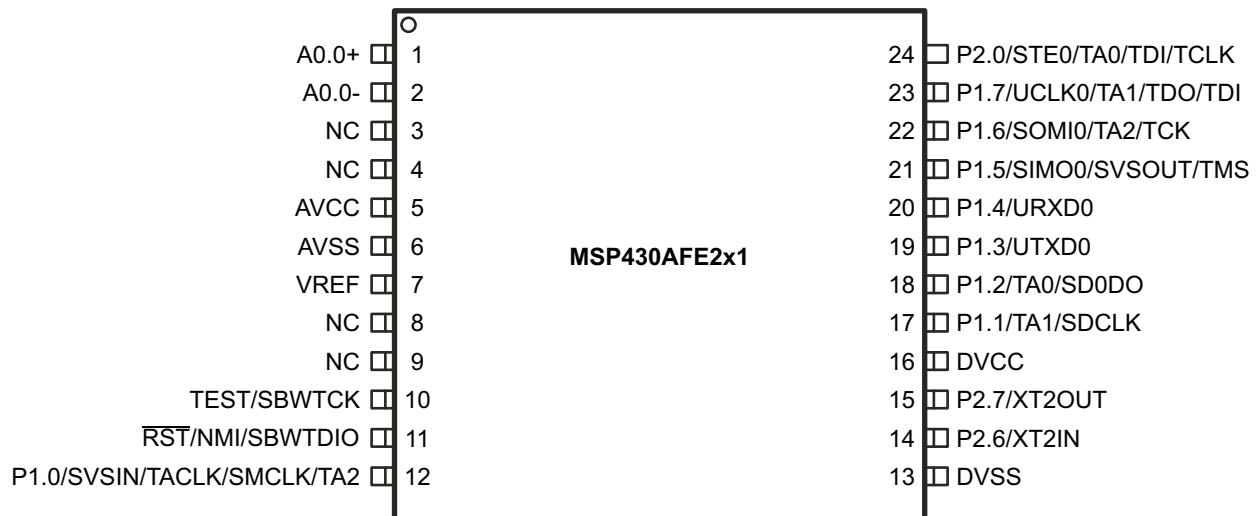


Pin Designation, MSP430AFE2x2IPW



A. Connect NC pins to analog ground (AVSS)

Pin Designation, MSP430AFE2x1IPW



B. Connect NC pins to analog ground (AVSS)

Table 2. Terminal Functions

TERMINAL		I/O	DESCRIPTION
NAME	NO.		
A0.0+	1	I	SD24_A positive analog input A0.0 ⁽¹⁾
A0.0-	2	I	SD24_A negative analog input A0.0 ⁽¹⁾
A1.0+	3	I	SD24_A positive analog input A1.0 (not available on MSP430AFE2x1) ⁽¹⁾
A1.0-	4	I	SD24_A negative analog input A1.0 (not available on MSP430AFE2x1) ⁽¹⁾
AVCC	5		Analog supply voltage, positive terminal. Must not power up prior to DVCC.
AVSS	6		Analog supply voltage, negative terminal
VREF	7	I/O	Input for an external reference voltage/ output for internal reference voltage (can be used as mid-voltage)
A2.0+	8	I	SD24_A positive analog input A2.0 (not available on MSP430AFE2x2 and MSP430AFE2x1) ⁽¹⁾
A2.0-	9	I	SD24_A negative analog input A2.0 (not available on MSP430AFE2x2 and MSP430AFE2x1) ⁽¹⁾
TEST/SBWTK	10	I	Selects test mode for JTAG pins on P1.5 to P1.7 and P2.0. The device protection fuse is connected to TEST. Spy-Bi-Wire test clock input for device programming and test.
$\overline{\text{RST}}$ /NMI/SBWDIO	11	I	Reset or nonmaskable interrupt input Spy-Bi-Wire test data input/output for device programming and test.
P1.0/SVSIN/TACLK/SMCLK/TA2	12	I/O	General-purpose digital I/O pin Analog input to supply voltage supervisor Timer_A3, clock signal TACLK input SMCLK signal output Timer_A3, compare: Out2 Output
DVSS	13		Digital supply voltage, negative terminal
P2.6/XT2IN	14	I/O	Input terminal of crystal oscillator General-purpose digital I/O pin
P2.7/XT2OUT	15	I/O	Output terminal of crystal oscillator General-purpose digital I/O pin
DVCC	16		Digital supply voltage, positive terminal.
P1.1/TA1/SDCLK	17	I/O	General-purpose digital I/O pin Timer_A3, capture: CCI1A and CCI1B inputs, compare: Out1 output SD24_A bit stream clock output
P1.2/TA0/SD0DO	18	I/O	General-purpose digital I/O pin Timer_A3, capture: CCI0A and CCI0B inputs, compare: Out0 output SD24_A bit stream data output for channel 0
P1.3/UTXD0/SD1DO	19	I/O	General-purpose digital I/O pin Transmit data out - USART0/UART mode SD24_A bit stream data output for channel 1 (not available on MSP430AFE2x1)
P1.4/URXD0/SD2DO	20	I/O	General-purpose digital I/O pin Receive data in - USART0/UART mode SD24_A bit stream data output for channel 2 (not available on MSP430AFE2x2 and MSP430AFE2x1)
P1.5/SIMO0/SVSOUT/TMS	21	I/O	General-purpose digital I/O Slave in/master out of USART0/SPI mode SVS: output of SVS comparator JTAG test mode select. TMS is used as an input port for device programming and test.
P1.6/SOMI0/TA2/TCK	22	I/O	General-purpose digital I/O pin Slave out/master in of USART0/SPI mode Timer_A3, compare: Out2 output JTAG test clock. TCK is the clock input port for device programming and test.
P1.7/UCLK0/TA1/TDO/TDI	23	I/O	General-purpose digital I/O pin External clock input - USART0/UART or SPI mode, clock output - USART0/SPI mode. Timer_A3, compare: Out1 output JTAG test data output port. TDO/TDI data output or programming data input terminal.

(1) It is recommended to short unused analog input pairs and connect them to analog ground.

Table 2. Terminal Functions (continued)

TERMINAL		I/O	DESCRIPTION
NAME	NO.		
P2.0/STE0/TA0/TDI/TCLK	24	I/O	General-purpose digital I/O pin Slave transmit enable - USART0/SPI mode. Timer_A3, compare: Out0 output JTAG test data input or test clock input for device programming and test.

SHORT-FORM DESCRIPTION

CPU

The MSP430™ CPU has a 16-bit RISC architecture that is highly transparent to the application. All operations, other than program-flow instructions, are performed as register operations in conjunction with seven addressing modes for source operand and four addressing modes for destination operand.

The CPU is integrated with 16 registers that provide reduced instruction execution time. The register-to-register operation execution time is one cycle of the CPU clock.

Four of the registers, R0 to R3, are dedicated as program counter, stack pointer, status register, and constant generator respectively. The remaining registers are general-purpose registers.

Peripherals are connected to the CPU using data, address, and control buses and can be handled with all instructions.

Instruction Set

The instruction set consists of 51 instructions with three formats and seven address modes. Each instruction can operate on word and byte data. [Table 3](#) shows examples of the three types of instruction formats; [Table 4](#) shows the address modes.

Program Counter	PC/R0
Stack Pointer	SP/R1
Status Register	SR/CG1/R2
Constant Generator	CG2/R3
General-Purpose Register	R4
General-Purpose Register	R5
General-Purpose Register	R6
General-Purpose Register	R7
General-Purpose Register	R8
General-Purpose Register	R9
General-Purpose Register	R10
General-Purpose Register	R11
General-Purpose Register	R12
General-Purpose Register	R13
General-Purpose Register	R14
General-Purpose Register	R15

Table 3. Instruction Word Formats

INSTRUCTION FORMAT	EXAMPLE	OPERATION
Dual operands, source-destination	ADD R4,R5	R4 + R5 → R5
Single operands, destination only	CALL R8	PC → (TOS), R8 → PC
Relative jump, unconditional/conditional	JNE	Jump-on-equal bit = 0

Table 4. Address Mode Descriptions

ADDRESS MODE	S ⁽¹⁾	D ⁽²⁾	SYNTAX	EXAMPLE	OPERATION
Register	✓	✓	MOV Rs,Rd	MOV R10,R11	R10 → R11
Indexed	✓	✓	MOV X(Rn),Y(Rm)	MOV 2(R5),6(R6)	M(2+R5) → M(6+R6)
Symbolic (PC relative)	✓	✓	MOV EDE,TONI		M(EDE) → M(TONI)
Absolute	✓	✓	MOV &MEM,&TCDAT		M(MEM) → M(TCDAT)
Indirect	✓		MOV @Rn,Y(Rm)	MOV @R10,Tab(R6)	M(R10) → M(Tab+R6)
Indirect autoincrement	✓		MOV @Rn+,Rm	MOV @R10+,R11	M(R10) → R11 R10 + 2 → R10
Immediate	✓		MOV #X,TONI	MOV #45,TONI	#45 → M(TONI)

(1) S = source

(2) D = destination

Operating Modes

The MSP430 microcontrollers have one active mode and five software-selectable low-power modes of operation. An interrupt event can wake up the device from any of the five low-power modes, service the request, and restore back to the low-power mode on return from the interrupt program.

The following six operating modes can be configured by software:

- Active mode (AM)
 - All clocks are active.
- Low-power mode 0 (LPM0)
 - CPU is disabled.
 - ACLK and SMCLK remain active. MCLK is disabled.
- Low-power mode 1 (LPM1)
 - CPU is disabled ACLK and SMCLK remain active. MCLK is disabled.
 - DCO dc-generator is disabled if DCO not used in active mode.
- Low-power mode 2 (LPM2)
 - CPU is disabled.
 - MCLK and SMCLK are disabled.
 - DCO dc-generator remains enabled.
 - ACLK remains active.
- Low-power mode 3 (LPM3)
 - CPU is disabled.
 - MCLK and SMCLK are disabled.
 - DCO dc-generator is disabled.
 - ACLK remains active.
- Low-power mode 4 (LPM4)
 - CPU is disabled.
 - ACLK is disabled.
 - MCLK and SMCLK are disabled.
 - DCO dc-generator is disabled.
 - Crystal oscillator is stopped.

Interrupt Vector Addresses

The interrupt vectors and the power-up starting address are located in the address range of 0FFFFh to 0FFE0h. The vector contains the 16-bit address of the appropriate interrupt handler instruction sequence.

If the reset vector (located at address 0FFFEh) contains 0FFFFh (for example, if flash is not programmed), the CPU goes into LPM4 immediately after power up.

Table 5. Interrupt Vector Addresses

INTERRUPT SOURCE	INTERRUPT FLAG	SYSTEM INTERRUPT	WORD ADDRESS	PRIORITY
Power up External reset Watchdog Flash key violation PC out-of-range ⁽¹⁾	PORIFG RSTIFG WDTIFG KEYV ⁽²⁾	Reset	0FFFEh	15, highest
NMI Oscillator fault Flash memory access violation	NMIIFG OFIFG ACCVIFG ^{(2) (3)}	(Non)maskable, (Non)maskable, (Non)maskable	0FFFCh	14
			0FFFAh	13
SD24_A	SD24CTLx SD24OVIFG SD24CTLx SD24IFG ^{(2) (4)}	Maskable	0FFF8h	12
			0FFF6h	11
Watchdog Timer	WDTIFG	Maskable	0FFF4h	10
USART0 Receive	URXIFG0	Maskable	0FFF2h	9
USART0 Transmit	UTXIFG0	Maskable	0FFF0h	8
			0FFEEh	7
Timer_A3	TA0CCR0 CCIFG ⁽⁴⁾	Maskable	0FFECh	6
Timer_A3	TA0CCR1 CCIFG, TA0CCR2 CCIFG, TA0CTL TAIFG ^{(2) (4)}	Maskable	0FFEAh	5
I/O Port P1 (eight flags)	P1IFG.0 to P1IFG.7 ^{(2) (4)}	Maskable	0FFE8h	4
			0FFE6h	3
			0FFE4h	2
I/O Port P2 (three flags)	P2IFG.0 to P2IFG.2 ^{(2) (4)}	Maskable	0FFE2h	1
			0FFE0h	0, lowest

(1) A reset is generated if the CPU tries to fetch instructions from within the module register memory address range (0h to 01FFh) or from within unused address range.

(2) Multiple source flags

(3) (Non)maskable: the individual interrupt-enable bit can disable an interrupt event, but the general interrupt enable cannot.

(4) Interrupt flags are located in the module.

Special Function Registers

Most interrupt and module enable bits are collected into the lowest address space. Special function register bits not allocated to a functional purpose are not physically present in the device. Simple software access is provided with this arrangement.

Legend




rw	Bit can be read and written.
rw-0, 1	Bit can be read and written. It is Reset or Set by PUC.
rw-(0), (1)	Bit can be read and written. It is Reset or Set by POR.
	SFR bit is not present in device.

Table 6. Interrupt Enable 1

Address	7	6	5	4	3	2	1	0
00h	UTXIE0	URXIE0	ACCVIE	NMIIE			OFIE	WDTIE
	rw-0	rw-0	rw-0	rw-0			rw-0	rw-0

- WDTIE Watchdog timer interrupt enable. Inactive if watchdog mode is selected. Active if watchdog timer is configured in interval timer mode.
- OFIE Oscillator fault interrupt enable
- NMIIE (Non)maskable interrupt enable
- ACCVIE Flash access violation interrupt enable
- URXIE0 USART0: UART and SPI receive interrupt enable
- UTXIE0 USART0: UART and SPI transmit interrupt enable

Table 7. Interrupt Enable 2










Address	7	6	5	4	3	2	1	0
01h								

Table 8. Interrupt Flag Register 1

Address	7	6	5	4	3	2	1	0
02h	UTXIFG0	URXIFG0		NMIIFG	RSTIFG	PORIFG	OFIFG	WDTIFG
	rw-1	rw-0		rw-0	rw-(0)	rw-(1)	rw-1	rw-(0)

- WDTIFG Set on watchdog timer overflow (in watchdog mode) or security key violation. Reset on V_{CC} power-up or a reset condition at \overline{RST}/NMI pin in reset mode.
- OFIFG Flag set on oscillator fault
- RSTIFG External reset interrupt flag. Set on a reset condition at \overline{RST}/NMI pin in reset mode. Reset on V_{CC} power up.
- PORIFG Power-on reset interrupt flag. Set on V_{CC} power up.
- NMIIFG Set via \overline{RST}/NMI -pin
- URXIFG0 USART0: UART and SPI receive interrupt flag
- UTXIFG0 USART0: UART and SPI transmit interrupt flag

Table 9. Interrupt Flag Register 2









Address	7	6	5	4	3	2	1	0
03h								

Table 10. Module Enable Register 1

Address	7	6	5	4	3	2	1	0
04h	UTXE0	URXE0 USPIE0						
	rw-0	rw-0						

URXE0 USART0: UART mode receive enable
 UTXE0 USART0: UART mode transmit enable
 USPIE0 USART0: SPI mode transmit and receive enable

Table 11. Module Enable Register 2

Address	7	6	5	4	3	2	1	0
05h								

Memory Organization

Table 12. Memory Organization

		MSP430AFE22x	MSP430AFE23x	MSP430AFE25x
Memory	Size	4 KB	8 KB	16 KB
Main: interrupt vector	Flash	0xFFFF to 0xFFE0	0xFFFF to 0xFFE0	0xFFFF to 0xFFE0
Main: code memory	Flash	0xFFFF to 0xF000	0xFFFF to 0xE000	0xFFFF to 0xC000
Information memory	Size	256 Byte	256 Byte	256 Byte
	Flash	0x10FFh to 0x1000	0x10FFh to 0x1000	0x10FFh to 0x1000
RAM	Size	256 Byte	512 Byte	512 Byte
		0x02FF to 0x0200	0x03FF to 0x0200	0x03FF to 0x0200
Peripherals	16-bit	0x01FF to 0x0100	0x01FF to 0x0100	0x01FF to 0x0100
	8-bit	0x00FF to 0x0010	0x00FF to 0x0010	0x00FF to 0x0010
	8-bit SFR	0x000F to 0x0000	0x000F to 0x0000	0x000F to 0x0000

Flash Memory

The flash memory can be programmed via the Spy-Bi-Wire/JTAG port or in-system by the CPU. The CPU can perform single-byte and single-word writes to the flash memory. Features of the flash memory include:

- Flash memory has n segments of main memory and four segments of information memory (A to D) of 64 bytes each. Each segment in main memory is 512 bytes in size.
- Segments 0 to n may be erased in one step, or each segment may be individually erased.
- Segments A to D can be erased individually, or as a group with segments 0 to n. Segments A to D are also called *information memory*.
- Segment A contains calibration data. After reset segment A is protected against programming and erasing. It can be unlocked but care should be taken not to erase this segment if the device-specific calibration data is required.

Peripherals

Peripherals are connected to the CPU through data, address, and control buses and can be handled using all instructions. For complete module descriptions, see the *MSP430x2xx Family User's Guide (SLAU144)*.

Oscillator and System Clock

The clock system is supported by the basic clock module that includes support for an internal digitally controlled oscillator (DCO), a high-frequency crystal oscillator, and an internal very-low-power low-frequency oscillator (VLO). The basic clock module is designed to meet the requirements of both low system cost and low power consumption. The internal DCO provides a fast turn-on clock source and stabilizes in less than 1 μ s. The basic clock module provides the following clock signals:

- Auxiliary clock (ACLK), sourced from the VLO
- Main clock (MCLK), the system clock used by the CPU
- Sub-Main clock (SMCLK), the sub-system clock used by the peripheral modules

**Table 13. DCO Calibration Data
(Provided From Factory in Flash Information Memory Segment A)**

DCO FREQUENCY	CALIBRATION REGISTER	SIZE	ADDRESS
8 MHz	CALBC1_8MHZ	byte	010FDh
	CALDCO_8MHZ	byte	010FCh
12 MHz	CALBC1_12MHZ	byte	010FBh
	CALDCO_12MHZ	byte	010FAh

Brownout, Supply Voltage Supervisor

The brownout circuit is implemented to provide the proper internal reset signal to the device during power on and power off. The supply voltage supervisor (SVS) circuitry detects if supply voltage drops below a user-selectable level and supports both supply voltage supervision (the device is automatically reset) and supply voltage monitoring (SVM) (the device is not automatically reset).

The CPU begins code execution after the brownout circuit releases the device reset. However, V_{CC} may not have ramped to $V_{CC(min)}$ at that time. The user must ensure that the default DCO settings are not changed until V_{CC} reaches $V_{CC(min)}$. If desired, the SVS circuit can be used to determine when V_{CC} reaches $V_{CC(min)}$.

Digital I/O

There are two I/O ports implemented: 8-bit port P1 and 3-bit port P2.

- All individual I/O bits are independently programmable.
- Any combination of input, output, and interrupt condition is possible.
- Edge-selectable interrupt input capability for all eight bits of port P1 and three bits of port P2.
- Read/write access to port-control registers is supported by all instructions.
- Each I/O has an individually programmable pullup/pulldown resistor.

Because there are only three I/O pins implemented from port P2, bits [5:1] of all port P2 registers read as 0, and write data is ignored.

Watchdog Timer (WDT+)

The primary function of the WDT+ module is to perform a controlled system restart after a software problem occurs. If the selected time interval expires, a system reset is generated. If the watchdog function is not needed in an application, the module can be disabled or configured as an interval timer and can generate interrupts at selected time intervals.

Timer_A3

Timer_A3 is a 16-bit timer/counter with three capture/compare registers. Timer_A3 can support multiple capture/compares, PWM outputs, and interval timing. Timer_A3 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

Table 14. Timer_A3 Signal Connections

INPUT PIN NUMBER	DEVICE INPUT SIGNAL	MODULE INPUT NAME	MODULE BLOCK	MODULE OUTPUT SIGNAL	OUTPUT PIN NUMBER
24-PIN PW					24-PIN PW
12 - P1.0	TACLK	TACLK	Timer	NA	
	ACLK	ACLK			
	SMCLK	SMCLK			
12 - P1.0	$\overline{\text{TACLK}}$	INCLK			
18 - P1.2	TA0	CCI0A	CCR0	TA0	18 - P1.2
18 - P1.2	TA0	CCI0B			24 - P2.0
	DVSS	GND			
	DVCC	VCC			
17 - P1.1	TA1	CCI1A	CCR1	TA1	17 - P1.1
17 - P1.1	TA1	CCI1B			23 - P1.7
	DVSS	GND			
	DVCC	VCC			
	DVSS	CCI2A	CCR2	TA2	12 - P1.0
	ACLK (internal)	CCI2B			22 - P1.6
	DVSS	GND			
	DVCC	VCC			

USART0

The MSP430AFE2xx devices have one hardware universal synchronous/asynchronous receive transmit (USART0) peripheral module that is used for serial data communication. The USART0 module supports synchronous SPI (3 or 4 pin) and asynchronous UART communication protocols, using double-buffered transmit and receive channels. The maximum operational frequency for the USART0 module is 8 MHz.

Hardware Multiplier

The multiplication operation is supported by a dedicated peripheral module. The module performs 16x16, 16x8, 8x16, and 8x8 bit operations. The module is capable of supporting signed and unsigned multiplication as well as signed and unsigned multiply and accumulate operations. The result of an operation can be accessed immediately after the operands have been loaded into the peripheral registers. No additional clock cycles are required.

SD24_A

The SD24_A module integrates up to three independent 24-bit sigma-delta A/D converters. Each channel is designed with fully differential analog input pair and programmable gain amplifier input stage. In addition to external analog inputs, an internal VCC sense and temperature sensor are also available.

Peripheral File Map

Table 15. Peripherals With Word Access

Timer_A3	Capture/compare register 2	TACCR2	0x0176
	Capture/compare register 1	TACCR1	0x0174
	Capture/compare register 0	TACCR0	0x0172
	Timer_A register	TAR	0x0170
	Capture/compare control 2	TACCTL2	0x0166
	Capture/compare control 1	TACCTL1	0x0164
	Capture/compare control 0	TACCTL0	0x0162
	Timer_A control	TACTL	0x0160
	Timer_A interrupt vector	TAIV	0x012E
Hardware Multiplier	Sum extend	SUMEXT	0x013E
	Result high word	RESHI	0x013C
	Result low word	RESLO	0x013A
	Second operand	OP2	0x0138
	Multiply signed + accumulate/operand 1	MACS	0x0136
	Multiply + accumulate/operand 1	MAC	0x0134
	Multiply signed/operand 1	MPYS	0x0132
	Multiply unsigned/operand 1	MPY	0x0130
Flash Memory	Flash control 3	FCTL3	0x012C
	Flash control 2	FCTL2	0x012A
	Flash control 1	FCTL1	0x0128
Watchdog Timer+	Watchdog/timer control	WDTCTL	0x0120
SD24_A (also see Table 16)	General Control	SD24CTL	0x0100
	Channel 0 Control	SD24CCTL0	0x0102
	Channel 1Control	SD24CCTL1	0x0104
	Channel 2 Control	SD24CCTL2	0x0106
	Channel 0 conversion memory	SD24MEM0	0x0110
	Channel 1 conversion memory	SD24MEM1	0x0112
	Channel 2 conversion memory	SD24MEM2	0x0114
	SD24 Interrupt vector word register	SD24IV	0x01AE

Table 16. Peripherals With Byte Access

SD24_A (also see Table 15)	Channel 0 Input Control	SD24INCTL0	0x00B0
	Channel 1 Input Control	SD24INCTL1	0x00B1
	Channel 2 Input Control	SD24INCTL2	0x00B2
	Channel 0 Preload	SD24PRE0	0x00B8
	Channel 1 Preload	SD24PRE1	0x00B9
	Channel 2 Preload	SD24PRE2	0x00BA
	Reserved (Internal SD24_A Configuration 1)	SD24CONF1	0x00BF
USART0	Transmit buffer	U0TXBUF	0x0077
	Receive buffer	U0RXBUF	0x0076
	Baud rate	U0BR1	0x0075
	Baud rate	U0BR0	0x0074
	Modulation control	U0MCTL	0x0073
	Receive control	U0RCTL	0x0072
	Transmit control	U0TCTL	0x0071
	USART control	U0CTL	0x0070
Basic Clock System+	Basic clock system control 3	BCSCTL3	0x0053
	Basic clock system control 2	BCSCTL2	0x0058
	Basic clock system control 1	BCSCTL1	0x0057
	DCO clock frequency control	DCOCTL	0x0056
Brownout, SVS	SVS control register (reset by brownout signal)	SVSCTL	0x0055
Port P2	Port P2 selection 2	P2SEL2	0x0042
	Port P2 resistor enable	P2REN	0x002F
	Port P2 selection	P2SEL	0x002E
	Port P2 interrupt enable	P2IE	0x002D
	Port P2 interrupt edge select	P2IES	0x002C
	Port P2 interrupt flag	P2IFG	0x002B
	Port P2 direction	P2DIR	0x002A
	Port P2 output	P2OUT	0x0029
	Port P2 input	P2IN	0x0028
Port P1	Port P1 selection 2 register	P1SEL2	0x0041
	Port P1 resistor enable	P1REN	0x0027
	Port P1 selection	P1SEL	0x0026
	Port P1 interrupt enable	P1IE	0x0025
	Port P1 interrupt edge select	P1IES	0x0024
	Port P1 interrupt flag	P1IFG	0x0023
	Port P1 direction	P1DIR	0x0022
	Port P1 output	P1OUT	0x0021
	Port P1 input	P1IN	0x0020
Special Function	SFR module enable 2	ME2	0x0005
	SFR module enable 1	ME1	0x0004
	SFR interrupt flag 2	IFG2	0x0003
	SFR interrupt flag 1	IFG1	0x0002
	SFR interrupt enable 2	IE2	0x0001
	SFR interrupt enable 1	IE1	0x0000

Absolute Maximum Ratings⁽¹⁾

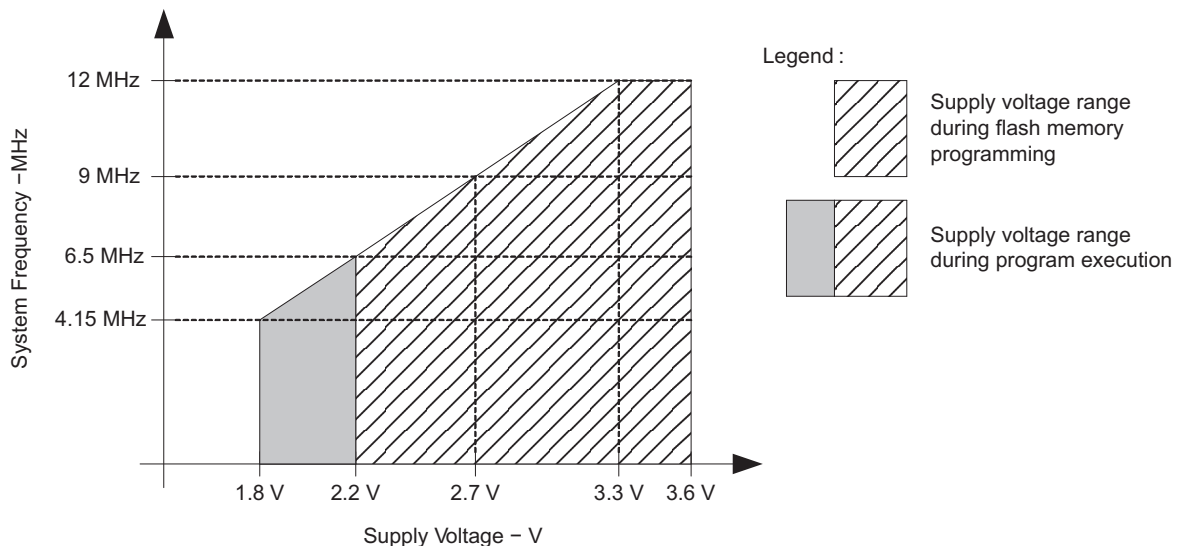
Voltage applied at V _{CC} to V _{SS}		-0.3 V to 4.1 V
Voltage applied to any pin ⁽²⁾		-0.3 V to V _{CC} + 0.3 V
Diode current at any device terminal		±2 mA
Storage temperature, T _{stg} ⁽³⁾	Unprogrammed device	-55°C to 150°C
	Programmed device	-40°C to 85°C

- (1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages referenced to V_{SS}. The JTAG fuse-blow voltage, V_{FB}, is allowed to exceed the absolute maximum rating. The voltage is applied to the TEST pin when blowing the JTAG fuse.
- (3) Higher temperature may be applied during board soldering process according to the current JEDEC J-STD-020 specification with peak reflow temperatures not higher than classified on the device label on the shipping boxes or reels.

Recommended Operating Conditions⁽¹⁾ (2)

			MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	AVCC = DVCC = V _{CC} ⁽¹⁾	During program execution ⁽³⁾	1.8	3.6	V
			During program/erase flash memory	2.2	3.6	V
V _{SS}	Supply voltage	AVSS = DVSS = V _{SS}		0		V
T _A	Operating free-air temperature		-40		85	°C
f _{SYSTEM}	Processor frequency (maximum MCLK frequency) ⁽¹⁾⁽²⁾ (see Figure 1)	V _{CC} = 1.8 V, Duty cycle = 50% ±10%	dc		4.15	MHz
		V _{CC} = 2.7 V, Duty cycle = 50% ±10%	dc		9	
		V _{CC} ≥ 3.3 V, Duty cycle = 50% ±10%	dc		12	

- (1) The MSP430 CPU is clocked directly with MCLK. Both the high and low phase of MCLK must not exceed the pulse width of the specified maximum frequency.
- (2) Modules might have a different maximum input clock specification. See the specification of the respective module in this data sheet.
- (3) The operating voltage range for SD24_A is 2.5 V to 3.6 V



- A. Minimum processor frequency is defined by system clock. Flash program or erase operations require a minimum V_{CC} of 2.2 V.
- B. If high frequency crystal used is above 12 MHz and selected to source CPU clock then MCLK divider should be programmed appropriately to run CPU below 8 MHz.

Figure 1. Operating Area

Active Mode Supply Current (into DV_{CC} + AV_{CC}) Excluding External Current⁽¹⁾

PARAMETER	TEST CONDITIONS	T _A	V _{CC}	MIN	TYP	MAX	UNIT
I _{AM, 1MHz} Active mode (AM) current at 1 MHz	f _{DCO} = f _{MCLK} = f _{SMCLK} = DCO default frequency (approximately 1 MHz), f _{ACLK} = f _{VLO} = 12 kHz, Program executes in flash, CPUOFF = 0, SCG0 = 0, SCG1 = 0, OSCOFF = 0		2.2 V		220		μA
			3 V		350		
I _{AM, 12MHz} Active mode (AM) current at 12 MHz	f _{DCO} = f _{MCLK} = f _{SMCLK} = 12 MHz, f _{ACLK} = f _{VLO} = 12 kHz, Program executes in flash, CPUOFF = 0, SCG0 = 0, SCG1 = 0, OSCOFF = 0		3.3 V		4.0	4.5	mA

(1) All inputs are tied to 0 V or V_{CC}. Outputs do not source or sink any current.

Typical Characteristics – Active-Mode Supply Current (Into DV_{CC} + AV_{CC})

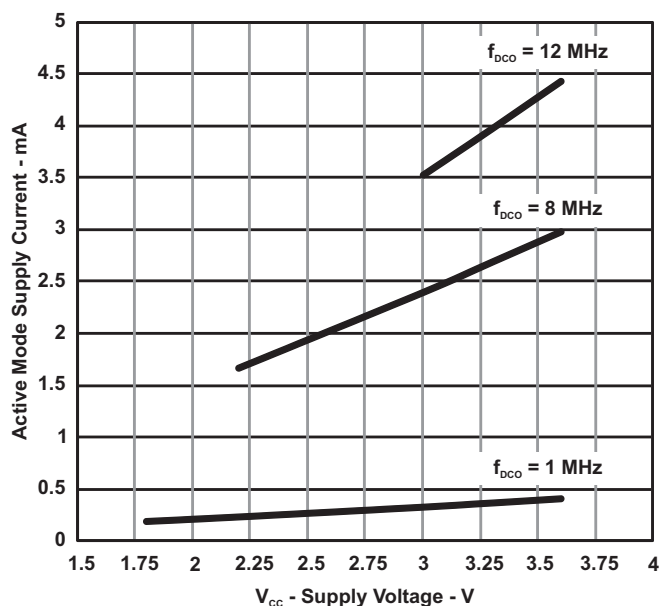


Figure 2. Active-Mode Current vs V_{CC}, T_A = 25°C

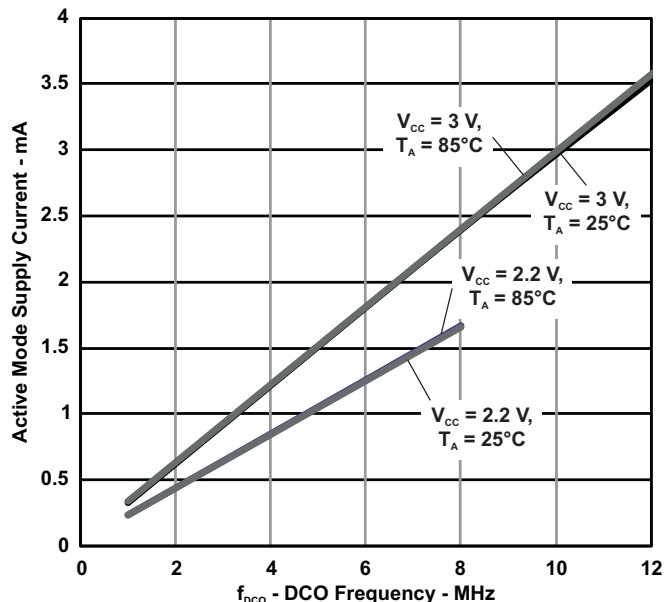


Figure 3. Active-Mode Current vs DCO Frequency

Low-Power-Mode Supply Currents (Into V_{CC}) Excluding External Current ⁽¹⁾

PARAMETER	TEST CONDITIONS	T_A	V_{CC}	MIN	TYP	MAX	UNIT
I_{LPM0} Low-power mode 0 (LPM0) current ⁽²⁾	$f_{MCLK} = 0$ MHz, $f_{SMCLK} = f_{DCO}$ = DCO default frequency (approximately 1 MHz), $f_{ACLK} = f_{VLO} = 12$ kHz, CPUOFF = 1, SCG0 = 0, SCG1 = 0, OSCOFF = 0	25°C	2.2 V		65		μ A
I_{LPM2} Low-power mode 2 (LPM2) current ⁽³⁾	$f_{MCLK} = f_{SMCLK} = 0$ MHz, f_{DCO} = DCO default frequency (approximately 1 MHz), $f_{ACLK} = f_{VLO} = 12$ kHz, CPUOFF = 1, SCG0 = 0, SCG1 = 1, OSCOFF = 0	25°C	2.2 V		22		μ A
$I_{LPM3,VLO}$ Low-power mode 3 (LPM3) current ⁽³⁾	$f_{DCO} = f_{MCLK} = f_{SMCLK} = 0$ MHz, $f_{ACLK} = f_{VLO} = 12$ kHz, CPUOFF = 1, SCG0 = 1, SCG1 = 1, OSCOFF = 0	25°C	2.2 V		0.5	1.0	μ A
I_{LPM4} Low-power mode 4 (LPM4) current ⁽⁴⁾		25°C	2.2 V		0.1	0.7	μ A
		85°C			1.1	2.5	

- (1) All inputs are tied to 0 V or V_{CC} . Outputs do not source or sink any current.
- (2) Current for brownout and WDT clocked by SMCLK included.
- (3) Current for brownout and WDT clocked by ACLK included.
- (4) Current for brownout included.

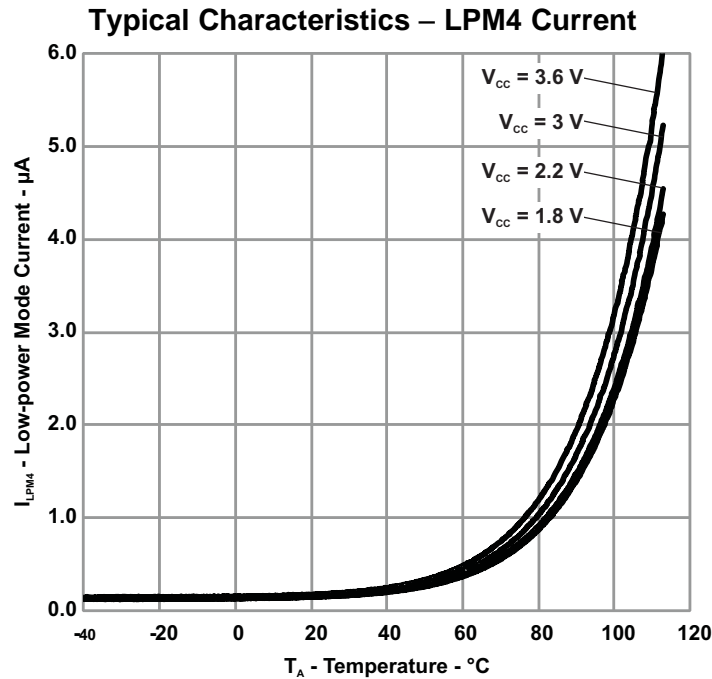


Figure 4. I_{LPM4} -- LPM4 Current vs Temperature

Schmitt-Trigger Inputs (Ports Px and $\overline{\text{RST}}/\text{NMI}$)

PARAMETER		TEST CONDITIONS	V_{CC}	MIN	TYP	MAX	UNIT
V_{IT+}	Positive-going input threshold voltage			0.45 V_{CC}		0.75 V_{CC}	V
			3 V	1.35	2.25		
V_{IT-}	Negative-going input threshold voltage			0.25 V_{CC}		0.55 V_{CC}	V
			3 V	0.75	1.65		
V_{hys}	Input voltage hysteresis ($V_{IT+} - V_{IT-}$)		3 V	0.3		1.0	V
R_{Pull}	Pullup/pulldown resistor (not $\overline{\text{RST}}/\text{NMI}$ pin)	For pullup: $V_{IN} = V_{SS}$; For pulldown: $V_{IN} = V_{CC}$	3 V	20	35	50	k Ω
C_I	Input capacitance	$V_{IN} = V_{SS}$ or V_{CC}			5		pF

Leakage Current (Ports Px)

PARAMETER		TEST CONDITIONS	V_{CC}	MIN	TYP	MAX	UNIT
$I_{lkg(Px.y)}$	High-impedance leakage current	(1)(2)	3 V			± 50	nA

- (1) The leakage current is measured with V_{SS} or V_{CC} applied to the corresponding pin(s), unless otherwise noted.
 (2) The leakage of the digital port pins is measured individually. The port pin is selected for input and the pullup/pulldown resistor is disabled.

Outputs (Ports Px)

PARAMETER		TEST CONDITIONS	V_{CC}	MIN	TYP	MAX	UNIT
V_{OH}	High-level output voltage	$I_{OH(max)} = -6 \text{ mA}^{(1)}$	3 V		$V_{CC} - 0.2$		V
V_{OL}	Low-level output voltage	$I_{OL(max)} = 6 \text{ mA}^{(1)}$	3 V		$V_{SS} + 0.2$		V

- (1) The maximum total current, $I_{OH(max)}$ and $I_{OL(max)}$, for all outputs combined, should not exceed $\pm 48 \text{ mA}$ to hold the maximum voltage drop specified.

Output Frequency (Ports Px)

PARAMETER		TEST CONDITIONS	V_{CC}	MIN	TYP	MAX	UNIT
$f_{Px.y}$	Port output frequency (with load)	Px.y, $C_L = 20 \text{ pF}$, $R_L = 1 \text{ k}\Omega^{(1)(2)}$	3 V		12		MHz
f_{Port_CLK}	Clock output frequency	Px.y, $C_L = 20 \text{ pF}^{(2)}$	3 V		16		MHz

- (1) A resistive divider with two 0.5-k Ω resistors between V_{CC} and V_{SS} is used as load. The output is connected to the center tap of the divider.
 (2) The output voltage reaches at least 10% and 90% V_{CC} at the specified toggle frequency.

Typical Characteristics – Outputs

One output loaded at a time.

TYPICAL LOW-LEVEL OUTPUT CURRENT
vs
LOW-LEVEL OUTPUT VOLTAGE

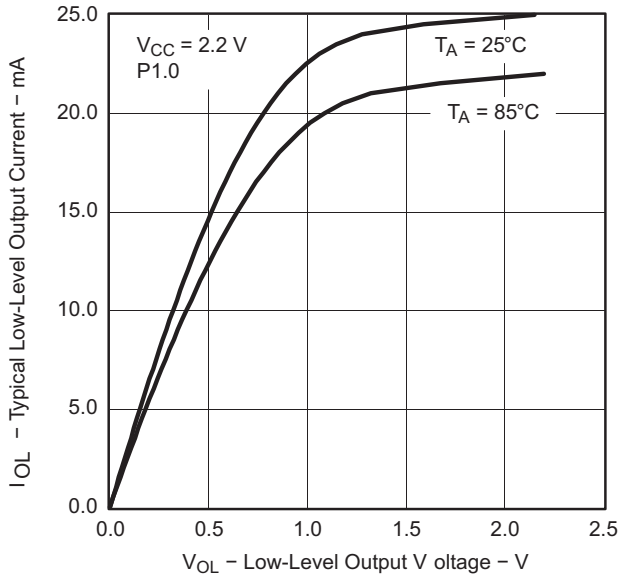


Figure 5.

TYPICAL LOW-LEVEL OUTPUT CURRENT
vs
LOW-LEVEL OUTPUT VOLTAGE

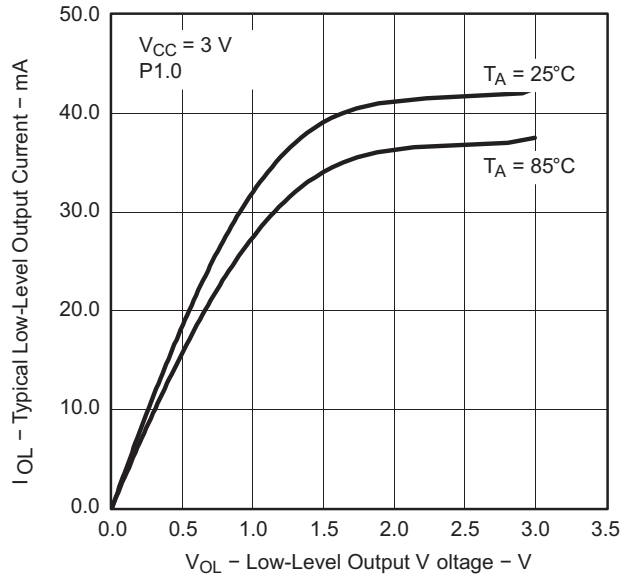


Figure 6.

TYPICAL HIGH-LEVEL OUTPUT CURRENT
vs
HIGH-LEVEL OUTPUT VOLTAGE

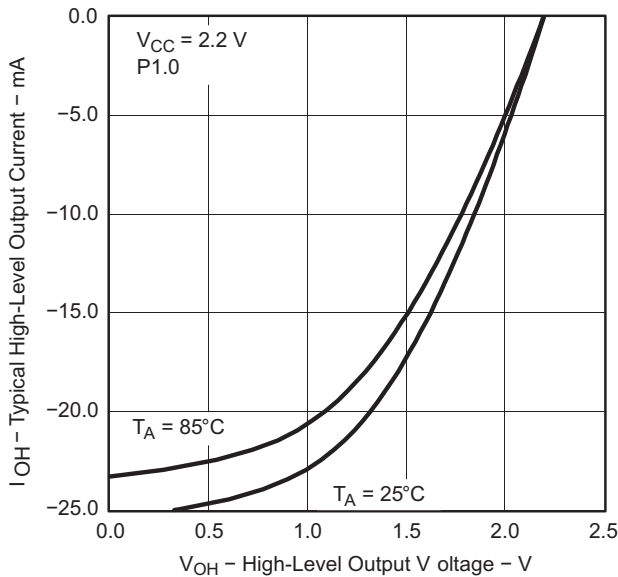


Figure 7.

TYPICAL HIGH-LEVEL OUTPUT CURRENT
vs
HIGH-LEVEL OUTPUT VOLTAGE

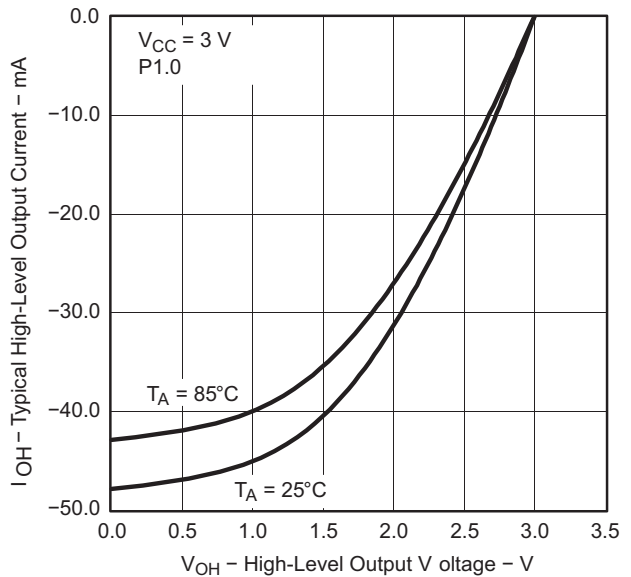


Figure 8.

POR/Brownout Reset (BOR)^{(1) (2)}

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
V _{CC(start)}	See Figure 9			0.7 × V _(B_IT-)		V
V _(B_IT-)	See Figure 9 through Figure 11			1.42		V
V _{hys(B_IT-)}	See Figure 9			120		mV
t _{d(BOR)}	See Figure 9			2000		μs
t _(reset)	Pulse length needed at $\overline{\text{RST}}/\text{NMI}$ pin to accepted reset internally	3 V	2			μs

- (1) The current consumption of the brownout module is already included in the I_{CC} current consumption data. The voltage level V_(B_IT-) + V_{hys(B_IT-)} is ≤ 1.8 V.
 (2) During power up, the CPU begins code execution following a period of t_{d(BOR)} after V_{CC} = V_(B_IT-) + V_{hys(B_IT-)}. The default DCO settings must not be changed until V_{CC} ≥ V_{CC(min)}, where V_{CC(min)} is the minimum supply voltage for the desired operating frequency.

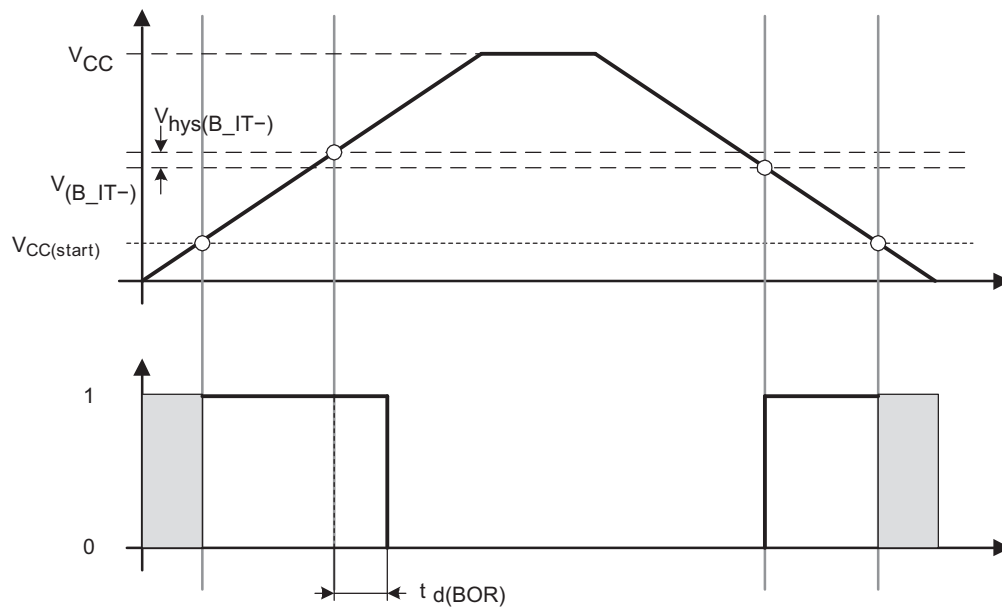


Figure 9. POR/Brownout Reset (BOR) vs Supply Voltage

Typical Characteristics – POR/Brownout Reset (BOR)

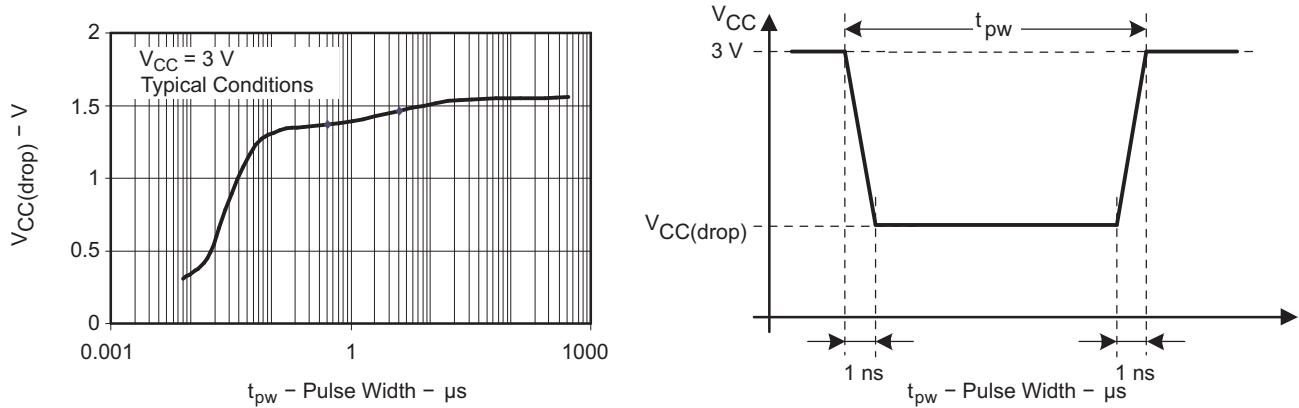


Figure 10. $V_{CC(drop)}$ Level With a Square Voltage Drop to Generate a POR/Brownout Signal

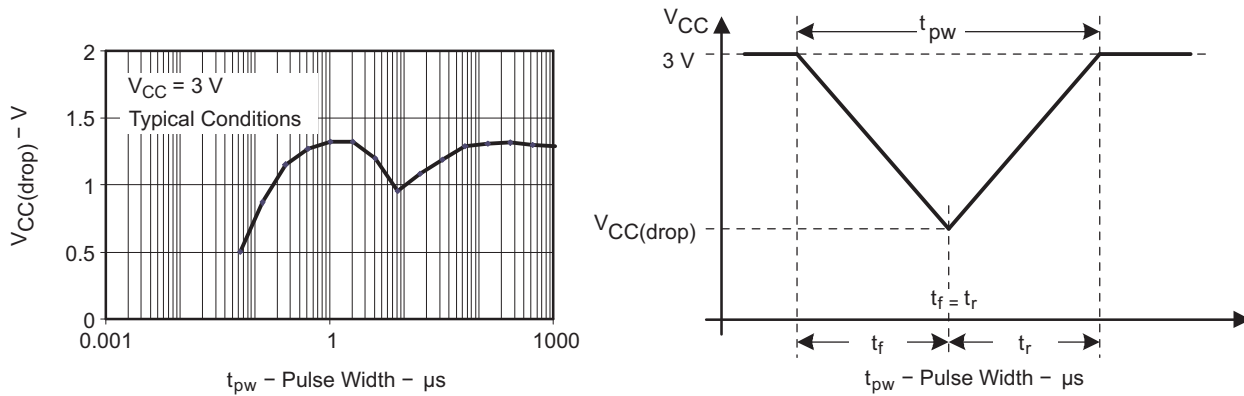


Figure 11. $V_{CC(drop)}$ Level With a Triangle Voltage Drop to Generate a POR/Brownout Signal

Supply Voltage Supervisor (SVS) / Supply Voltage Monitor (SVM)⁽¹⁾

PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{(SVSR)}$	$dV_{CC}/dt > 30 \text{ V/ms}$ (see Figure 12)			100		μs
	$dV_{CC}/dt \leq 30 \text{ V/ms}$			2000		
$t_{d(SV\text{Son})}$	SVS on, switch from VLD = 0 to VLD \neq 0, $V_{CC} = 3 \text{ V}$			100		μs
t_{settle}	VLD \neq 0 ⁽²⁾			12		μs
$V_{(SV\text{Sstart})}$	VLD \neq 0, $V_{CC}/dt \leq 3 \text{ V/s}$ (see Figure 12)			1.55	1.7	V
$V_{\text{hys}(SV\text{S_IT-})}$	$V_{CC}/dt \leq 3 \text{ V/s}$ (see Figure 12)	VLD = 1		120		mV
		VLD = 2 to 14		15		mV
	$V_{CC}/dt \leq 3 \text{ V/s}$ (see Figure 12), external voltage applied on SVSIN	VLD = 15		10		mV
$V_{(SV\text{S_IT-})}$	$V_{CC}/dt \leq 3 \text{ V/s}$ (see Figure 12)	VLD = 1	1.8	1.9	2.05	V
		VLD = 2		2.1		
		VLD = 3		2.2		
		VLD = 4		2.3		
		VLD = 5	2.24	2.4	2.6	
		VLD = 6		2.5		
		VLD = 7		2.65		
		VLD = 8		2.8		
		VLD = 9	2.69	2.9	3.13	
		VLD = 10		3.05		
		VLD = 11		3.2		
		VLD = 12		3.35		
		VLD = 13	3.24	3.5	3.76 ⁽³⁾	
		VLD = 14		3.7 ⁽³⁾		
$V_{CC}/dt \leq 3 \text{ V/s}$ (see Figure 12), external voltage applied on SVSIN	VLD = 15	1.1	1.2	1.3		
$I_{CC(SVS)}$ ⁽¹⁾	VLD \neq 0, $V_{CC} = 3 \text{ V}$			12	17	μA

(1) The current consumption of the SVS module is not included in the I_{CC} current consumption data.

(2) t_{settle} is the settling time that the comparator o/p needs to have a stable level after VLD is switched VLD \neq 0 to a different VLD value somewhere between 2 and 15. The overdrive is assumed to be $> 50 \text{ mV}$.

(3) The recommended operating voltage range is limited to 3.6 V.

Typical Characteristics – SVS

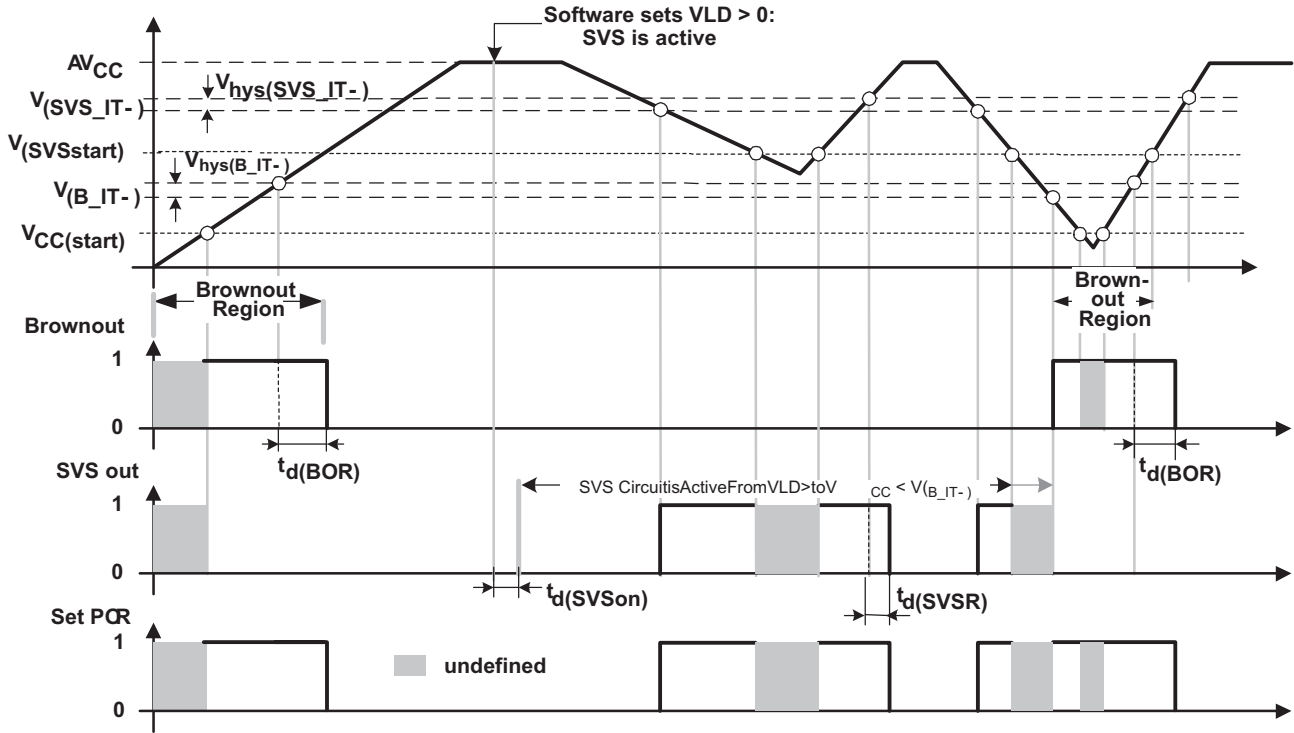


Figure 12. SVS Reset (SVSR) vs Supply Voltage

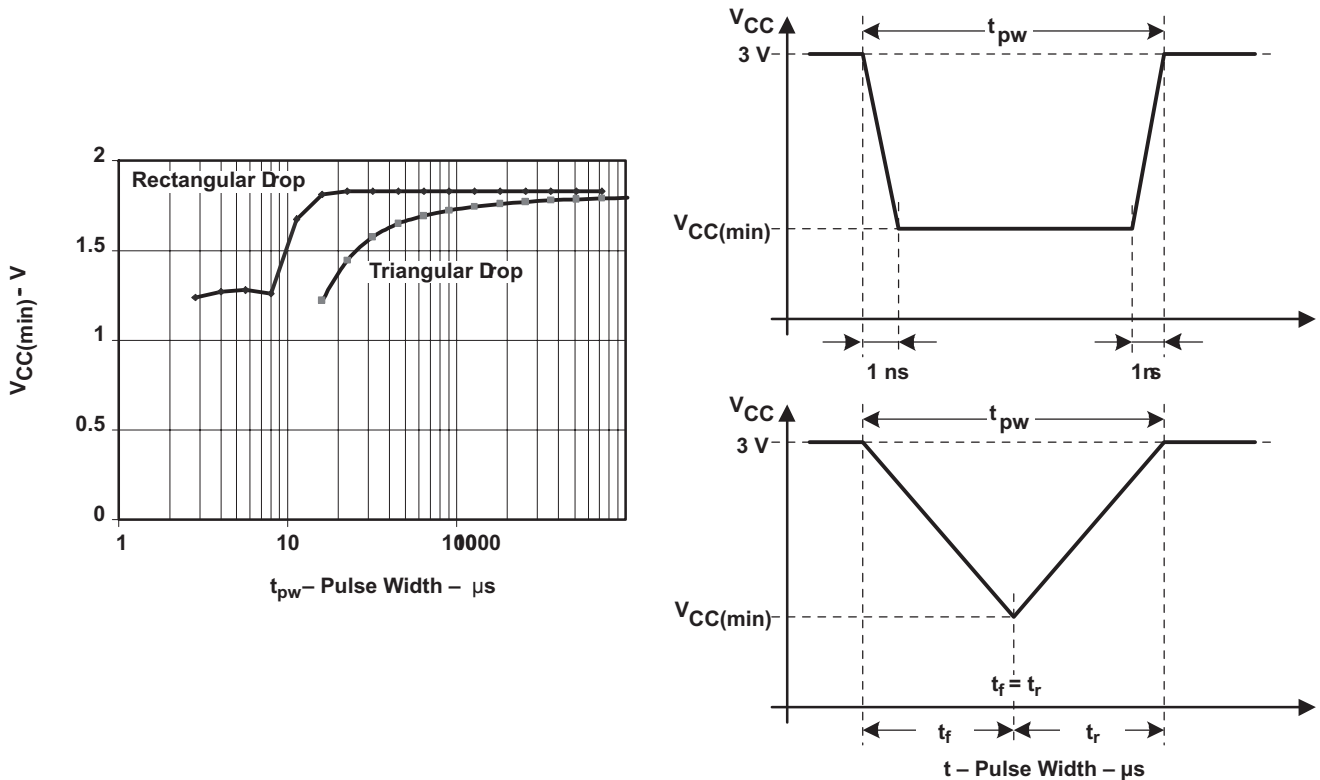


Figure 13. $V_{CC(min)}$ With a Square Voltage Drop and a Triangle Voltage Drop to Generate an SVS Signal

Main DCO Characteristics

- All ranges selected by RSELx overlap with RSELx + 1: RSELx = 0 overlaps RSELx = 1, ... RSELx = 14 overlaps RSELx = 15.
- DCO control bits DCOx have a step size as defined by parameter S_{DCO}.
- Modulation control bits MODx select how often f_{DCO(RSEL,DCO+1)} is used within the period of 32 DCOCLK cycles. The frequency f_{DCO(RSEL,DCO)} is used for the remaining cycles. The frequency is an average equal to:

$$f_{\text{average}} = \frac{32 \times f_{\text{DCO(RSEL,DCO)}} \times f_{\text{DCO(RSEL,DCO+1)}}}{\text{MOD} \times f_{\text{DCO(RSEL,DCO)}} + (32 - \text{MOD}) \times f_{\text{DCO(RSEL,DCO+1)}}}$$

DCO Frequency

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
V _{CC}	Supply voltage range	RSELx < 14		1.8		3.6	V
		RSELx = 14		2.2		3.6	
		RSELx = 15		3.0		3.6	
f _{DCO(0,0)}	DCO frequency (0, 0)	RSELx = 0, DCOx = 0, MODx = 0	3.3 V	0.06	0.10	0.14	MHz
f _{DCO(0,3)}	DCO frequency (0, 3)	RSELx = 0, DCOx = 3, MODx = 0	3.3 V		0.12		MHz
f _{DCO(1,3)}	DCO frequency (1, 3)	RSELx = 1, DCOx = 3, MODx = 0	3.3 V		0.15		MHz
f _{DCO(2,3)}	DCO frequency (2, 3)	RSELx = 2, DCOx = 3, MODx = 0	3.3 V		0.21		MHz
f _{DCO(3,3)}	DCO frequency (3, 3)	RSELx = 3, DCOx = 3, MODx = 0	3.3 V		0.30		MHz
f _{DCO(4,3)}	DCO frequency (4, 3)	RSELx = 4, DCOx = 3, MODx = 0	3.3 V		0.41		MHz
f _{DCO(5,3)}	DCO frequency (5, 3)	RSELx = 5, DCOx = 3, MODx = 0	3.3 V		0.58		MHz
f _{DCO(6,3)}	DCO frequency (6, 3)	RSELx = 6, DCOx = 3, MODx = 0	3.3 V		0.80		MHz
f _{DCO(7,3)}	DCO frequency (7, 3)	RSELx = 7, DCOx = 3, MODx = 0	3.3 V		1.15		MHz
f _{DCO(8,3)}	DCO frequency (8, 3)	RSELx = 8, DCOx = 3, MODx = 0	3.3 V		1.60		MHz
f _{DCO(9,3)}	DCO frequency (9, 3)	RSELx = 9, DCOx = 3, MODx = 0	3.3 V		2.30		MHz
f _{DCO(10,3)}	DCO frequency (10, 3)	RSELx = 10, DCOx = 3, MODx = 0	3.3 V		3.40		MHz
f _{DCO(11,3)}	DCO frequency (11, 3)	RSELx = 11, DCOx = 3, MODx = 0	3.3 V		4.25		MHz
f _{DCO(12,3)}	DCO frequency (12, 3)	RSELx = 12, DCOx = 3, MODx = 0	3.3 V		5.80		M Hz
f _{DCO(13,3)}	DCO frequency (13, 3)	RSELx = 13, DCOx = 3, MODx = 0	3.3 V		7.80		MHz
f _{DCO(14,3)}	DCO frequency (14, 3)	RSELx = 14, DCOx = 3, MODx = 0	3.3 V	8.6	11.25	13.9	MHz
f _{DCO(15,3)}	DCO frequency (15, 3)	RSELx = 15, DCOx = 3, MODx = 0	3.3 V		15.30		MHz
f _{DCO(15,7)}	DCO frequency (15, 7)	RSELx = 15, DCOx = 7, MODx = 0	3.3 V		21.00		MHz
S _{RSEL}	Frequency step between range RSEL and RSEL+1	S _{RSEL} = f _{DCO(RSEL+1,DCO)} /f _{DCO(RSEL,DCO)}	3.3 V		1.35		ratio
S _{DCO}	Frequency step between tap DCO and DCO+1	S _{DCO} = f _{DCO(RSEL,DCO+1)} /f _{DCO(RSEL,DCO)}	3.3 V		1.08		ratio
	Duty cycle	Measured at SMCLK output	3.3 V		50		%

Calibrated DCO Frequencies – Tolerance

PARAMETER	TEST CONDITIONS	T _A	V _{CC}	MIN	TYP	MAX	UNIT
8-MHz tolerance over temperature ⁽¹⁾	BCSCTL1 = CALBC1_8MHZ, DCOCTL = CALDCO_8MHZ, calibrated at 30°C and 3.3V	0°C to 85°C	3.3 V	7.76	8	8.24	MHz
8-MHz tolerance over V _{CC}	BCSCTL1 = CALBC1_8MHZ, DCOCTL = CALDCO_8MHZ, calibrated at 30°C and 3.3V	30°C	2.7 V to 3.6 V	7.76	8	8.24	MHz
8-MHz tolerance overall	BCSCTL1 = CALBC1_8MHZ, DCOCTL = CALDCO_8MHZ, calibrated at 30°C and 3.3V	-40°C to 85°C	2.7 V to 3.6 V	7.52	8	8.48	MHz
12-MHz tolerance over temperature ⁽¹⁾	BCSCTL1 = CALBC1_12MHZ, DCOCTL = CALDCO_12MHZ, calibrated at 30°C and 3.3V	0°C to 85°C	3.3 V	11.64	12	12.36	MHz
12-MHz tolerance over V _{CC}	BCSCTL1 = CALBC1_12MHZ, DCOCTL = CALDCO_12MHZ, calibrated at 30°C and 3.3V	30°C	3.3 V to 3.6 V	11.64	12	12.36	MHz
12-MHz tolerance overall	BCSCTL1 = CALBC1_12MHZ, DCOCTL = CALDCO_12MHZ, calibrated at 30°C and 3.3V	-40°C to 85°C	3.3 V to 3.6 V	11.28	12	12.72	MHz

(1) This is the frequency change from the measured frequency at 30°C over temperature.

Wake-Up From Lower-Power Modes (LPM3/4)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
t _{DCO,LPM3/4}	DCO clock wake-up time from LPM3/4 ⁽¹⁾	f _{DCO} = DCO default frequency (approximately 1 MHz) 3 V		1.5		μs
t _{CPU,LPM3/4}	CPU wake-up time from LPM3/4 ⁽²⁾			1 / f _{MCLK} + t _{DCO,LPM3/4}		μs

- (1) The DCO clock wake-up time is measured from the edge of an external wake-up signal (for example, a port interrupt) to the first clock edge observable externally on a clock pin (MCLK or SMCLK).
(2) Parameter applicable only if DCOCLK is used for MCLK.

Typical Characteristics – DCO Clock Wake-Up Time From LPM3/4

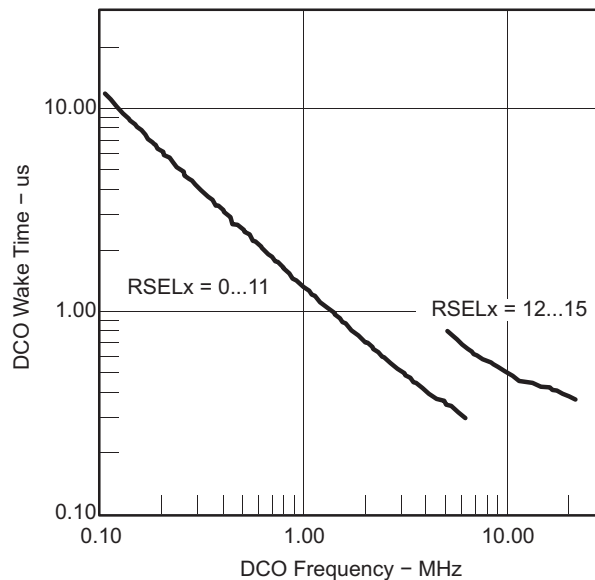


Figure 14. Clock Wake-Up Time From LPM3 vs DCO Frequency

Internal Very-Low-Power Low-Frequency Oscillator (VLO)

PARAMETER		T _A	V _{CC}	MIN	TYP	MAX	UNIT
f _{VLO}	VLO frequency	-40°C to 85°C	3 V	4	12	22	kHz
df _{VLO} /dT	VLO frequency temperature drift ⁽¹⁾	-40°C to 85°C	3 V		0.5		%/°C
df _{VLO} /dV _{CC}	VLO frequency supply voltage drift ⁽²⁾	25°C	1.8 V to 3.6 V		4		%/V

(1) Calculated using the box method: [MAX(-40...85°C) - MIN(-40...85°C)]/MIN(-40...85°C)/[85°C - (-40°C)]

(2) Calculated using the box method: [MAX(1.8...3.6 V) - MIN(1.8...3.6 V)]/MIN(1.8...3.6 V)/(3.6 V - 1.8 V)

Crystal Oscillator (XT2)⁽¹⁾

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f _{XT2,HF0}	XT2 oscillator crystal frequency, HF mode 0	XT2OFF = 0, XT2Sx = 0	1.8 V to 3.6 V	0.4		1	MHz
f _{XT2,HF1}	XT2 oscillator crystal frequency, HF mode 1	XT2OFF = 0, XT2Sx = 1	1.8 V to 3.6 V	1		4	MHz
f _{XT2,HF2}	XT2 oscillator crystal frequency, HF mode 2	XT2OFF = 0, XT2Sx = 2	1.8 V to 2.2 V	2		10	MHz
			2.2 V to 3.0 V	2		12	
			3.0 V to 3.6 V	2		16	
f _{XT2,HF,logic}	XT2 oscillator logic-level square-wave input frequency, HF mode	XT2OFF = 0, XT2Sx = 3	1.8 V to 2.2 V	0.4		10	MHz
			2.2 V to 3.0 V	0.4		12	
			3.0 V to 3.6 V	0.4		16	
O _{AHF}	Oscillation allowance for HF crystals (see Figure 15 and Figure 16)	XT2OFF = 0, XT2Sx = 0 f _{XT2,HF} = 1 MHz, C _{L,eff} = 15 pF			2700		Ω
		XT2OFF = 0, XT2Sx = 1 f _{XT2,HF} = 4 MHz, C _{L,eff} = 15 pF			800		
		XT2OFF = 0, XT2Sx = 2 f _{XT2,HF} = 16 MHz, C _{L,eff} = 15 pF			300		
C _{L,eff}	Integrated effective load capacitance, HF mode ⁽²⁾	XT2OFF = 0 ⁽³⁾			1		pF
Duty cycle		XT2OFF = 0, Measured at P1.0/SVSIN/TACLK/SMCLK/TA2, f _{XT2,HF} = 10 MHz	3 V	40	50	60	%
		XT2OFF = 0, Measured at P1.0/SVSIN/TACLK/SMCLK/TA2, f _{XT2,HF} = 16 MHz		40	50	60	
f _{Fault,HF}	Oscillator fault frequency ⁽⁴⁾	XT2OFF = 0, XT2Sx = 3 ⁽⁵⁾	3 V	30		300	kHz

(1) To improve EMI on the XT2 oscillator the following guidelines should be observed:

- (a) Keep the trace between the device and the crystal as short as possible.
 - (b) Design a good ground plane around the oscillator pins.
 - (c) Prevent crosstalk from other clock or data lines into oscillator pins XT2IN and XT2OUT.
 - (d) Avoid running PCB traces underneath or adjacent to the XT2IN and XT2OUT pins.
 - (e) Use assembly materials and praxis to avoid any parasitic load on the oscillator XT2IN and XT2OUT pins.
 - (f) If conformal coating is used, ensure that it does not induce capacitive/resistive leakage between the oscillator pins.
- (2) Includes parasitic bond and package capacitance (approximately 2 pF per pin). Because the PCB adds additional capacitance, it is recommended to verify the correct load by measuring the ACLK frequency. For a correct setup, the effective load capacitance should always match the specification of the used crystal.
 - (3) Requires external capacitors at both terminals. Values are specified by crystal manufacturers.
 - (4) Frequencies below the MIN specification set the fault flag, frequencies above the MAX specification do not set the fault flag, and frequencies in between might set the flag.
 - (5) Measured with logic-level input frequency, but also applies to operation with crystals.

Typical Characteristics – XT2 Oscillator

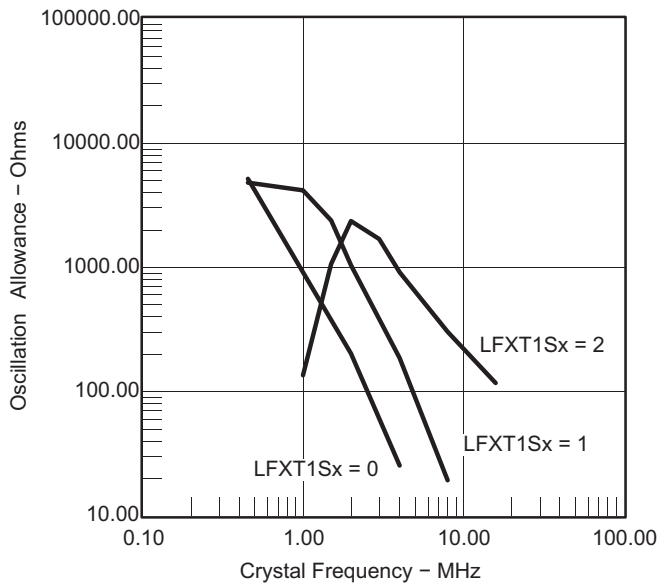


Figure 15. Oscillation Allowance vs Crystal Frequency, $C_{L,eff} = 15 \text{ pF}$, $T_A = 25^\circ\text{C}$

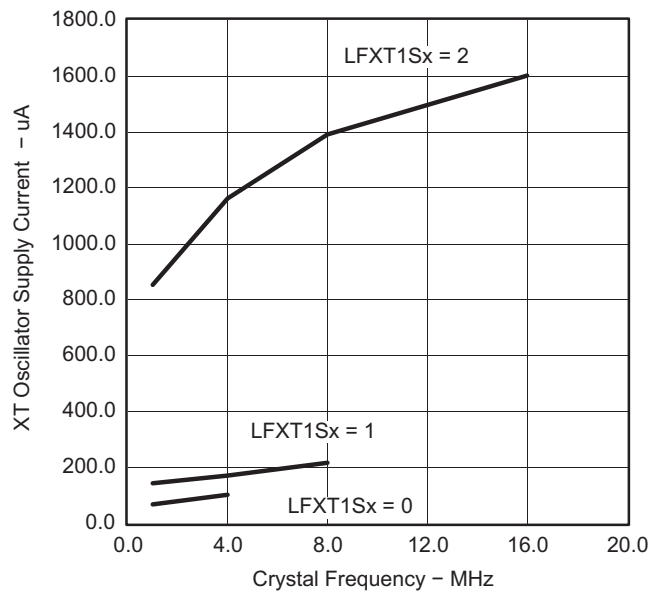


Figure 16. XT2 Oscillator Supply Current vs Crystal Frequency, $C_{L,eff} = 15 \text{ pF}$, $T_A = 25^\circ\text{C}$

SD24_A, Power Supply and Recommended Operating Conditions

PARAMETER		TEST CONDITIONS	V_{CC}	MIN	TYP	MAX	UNIT		
AV_{CC}	Analog supply voltage	$AV_{CC} = DV_{CC}$ $AV_{SS} = DV_{SS} = 0 \text{ V}$		2.5		3.6	V		
I_{SD24}	Analog supply current: 1 active SD24_A channel including internal reference	SD24LP = 0, $f_{SD24} = 1 \text{ MHz}$, SD24OSR = 256	3 V			GAIN: 1, 2	800	1100	μA
						GAIN: 4, 8, 16	900		
						GAIN: 32	1200		
		SD24LP = 1, $f_{SD24} = 0.5 \text{ MHz}$, SD24OSR = 256				GAIN: 1	800		
GAIN: 32	900								
f_{SD24}	Analog front-end input clock frequency	SD24LP = 0 (low-power mode disabled)	3 V			0.03	1	1.1	MHz
		SD24LP = 1 (low-power mode enabled)				0.03	0.5		

SD24_A, Input Range⁽¹⁾

PARAMETER	TEST CONDITIONS		V _{CC}	MIN	TYP	MAX	UNIT
V _{ID,FSR}	Differential full scale input voltage range	Bipolar mode, SD24UNI = 0		-V _{REF} / 2GAIN		+V _{REF} / 2GAIN	mV
		Unipolar mode, SD24UNI = 1		0		+V _{REF} / 2GAIN	
V _{ID}	Differential input voltage range for specified performance ⁽²⁾	SD24REFON = 1		SD24GAINx = 1		±500	mV
				SD24GAINx = 2		±250	
				SD24GAINx = 4		±125	
				SD24GAINx = 8		±62	
				SD24GAINx = 16		±31	
				SD24GAINx = 32		±15	
Z _I	Input impedance (one input pin to AVSS)	f _{SD24} = 1 MHz		SD24GAINx = 1		200	kΩ
				SD24GAINx = 32	3 V	75	
Z _{ID}	Differential input impedance (IN+ to IN-)	f _{SD24} = 1 MHz		SD24GAINx = 1	300	400	kΩ
				SD24GAINx = 32	3 V	100	
V _I	Absolute input voltage range			AVSS - 1		AVCC	V
V _{IC}	Common-mode input voltage range			AVSS - 1		AVCC	V

(1) All parameters pertain to each SD24_A channel.

(2) The full-scale range is defined by V_{FSR+} = +(V_{REF}/2)/GAIN and V_{FSR-} = -(V_{REF}/2)/GAIN. If V_{REF} is sourced externally, the analog input range should not exceed 80% of V_{FSR+} or V_{FSR-}; that is, V_{ID} = 0.8 V_{FSR-} to 0.8 V_{FSR+}. If V_{REF} is sourced internally, the given V_{ID} ranges apply.

SD24_A, Performance (f_{SD24} = 1 MHz, SD24OSRx = 256, SD24REFON = 1)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT	
G	Nominal gain	3 V		SD24GAINx = 1	1		
				SD24GAINx = 2	1.96		
				SD24GAINx = 4	3.86		
				SD24GAINx = 8	7.62		
				SD24GAINx = 16	15.04		
				SD24GAINx = 32	28.35		
E _{OS}	Offset error	3 V		SD24GAINx = 1	±0.2	%FSR	
				SD24GAINx = 32	±1.5		
ΔEOS/ΔT	Offset error temperature coefficient	3 V		SD24GAINx = 1	±4	±20	ppm FSR/°C
				SD24GAINx = 32	±20	±100	
CMRR	Common-mode rejection ratio	3 V		SD24GAINx = 1, Common-mode input signal: V _{ID} = 500 mV, f _{IN} = 50 Hz, 100 Hz	>90	dB	
				SD24GAINx = 32, Common-mode input signal: V _{ID} = 16 mV, f _{IN} = 50 Hz, 100 Hz	>75		
AC PSRR	AC power supply rejection ratio	3 V		SD24GAINx = 1, V _{CC} = 3 V ± 100 mV, f _{VCC} = 50 Hz	>80	dB	
XT	Crosstalk	3 V		SD24GAINx = 1, V _{ID} = 500 mV, f _{IN} = 50 Hz, 100 Hz	<-100	dB	

SD24_A, Temperature Sensor and Built-In V_{CC} Sense

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT		
TC _{Sensor}	Sensor temperature coefficient		1.18	1.32	1.46	mV/°C		
V _{Offset,sensor}	Sensor offset voltage		-100		100	mV		
V _{Sensor}	Sensor output voltage ⁽¹⁾⁽²⁾	3 V	Temperature sensor voltage at T _A = 85°C		420	475	515	mV
			Temperature sensor voltage at T _A = 30°C		350	402	442	
V _{CC,Sense}	V _{CC} divider at input 5	f _{SD24} = 1 MHz, SD24OSRx = 256, SD24REFON = 1	V _{CC} /1			1	V	
R _{Source,VCC}	Source resistance of V _{CC} divider at input 5		20				kΩ	

(1) The following formula can be used to calculate the temperature sensor output voltage:

$$V_{\text{Sensor,typ}} = TC_{\text{Sensor}} (273 + T [^{\circ}\text{C}]) + V_{\text{Offset,sensor}} [\text{mV}]$$

(2) Results based on characterization and/or production test, not TC_{Sensor} or V_{Offset,sensor}. Measured with f_{SD24} = 1 MHz, SD24OSRx = 256, SD24REFON = 1.

SD24_A, Built-In Voltage Reference

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT	
V _{REF}	Internal reference voltage	SD24REFON = 1, SD24VMIDON = 0	3 V	1.14	1.2	1.26	V
I _{REF}	Reference supply current	SD24REFON = 1, SD24VMIDON = 0	3 V		200	320	μA
TC	Temperature coefficient	SD24REFON = 1, SD24VMIDON = 0 ⁽¹⁾	3 V		18	50	ppm/°C
C _{REF}	V _{REF} load capacitance	SD24REFON = 1, SD24VMIDON = 0 ⁽²⁾			100		nF
I _{LOAD}	V _{REF(I)} maximum load current	SD24REFON = 1, SD24VMIDON = 0	3 V			±200	nA
t _{ON}	Turn-on time	SD24REFON = 0→1, SD24VMIDON = 0, C _{REF} = 100nF	3 V		5		ms
DC PSR	DC power supply rejection ΔV _{REF} /ΔV _{CC}	SD24REFON = 1, SD24VMIDON = 0, V _{CC} = 2.5 V to 3.6 V			100		μV/V

(1) Calculated using the box method: (MAX(-40...85°C) - MIN(-40...85°C)) / MIN(-40...85°C) / (85°C - (-40°C))

(2) There is no capacitance required on V_{REF}. However, a capacitance of at least 100 nF is recommended to reduce any reference voltage noise.

SD24_A, Reference Output Buffer

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT	
V _{REF,BUF}	Reference buffer output voltage	SD24REFON = 1, SD24VMIDON = 1	3 V		1.2		V
I _{REF,BUF}	Reference supply + reference output buffer quiescent current	SD24REFON = 1, SD24VMIDON = 1	3 V		430	650	μA
C _{REF(O)}	Required load capacitance on V _{REF}	SD24REFON = 1, SD24VMIDON = 1			470		nF
I _{LOAD,Max}	Maximum load current on V _{REF}	SD24REFON = 1, SD24VMIDON = 1	3 V			±1	mA
	Maximum voltage variation vs load current	I _{LOAD} = 0 to 1 mA	3 V		-15	+15	mV
t _{ON}	Turn-on time	SD24REFON = 0→1, SD24VMIDON = 0→1, C _{REF} = 470 nF	3 V		100		μs

SD24_A, External Reference Input

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
V _{REF(I)} Input voltage range	SD24REFON = 0	3 V	1.0	1.25	1.5	V
I _{REF(I)} Input current	SD24REFON = 0	3 V			50	nA

USART0

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{USART} USART clock frequency				8	MHz
t _(T) USART0: deglitch time ⁽¹⁾	V _{CC} = 3 V, SYNC = 0, UART mode	150	280	500	ns

- (1) The signal applied to the USART0 receive signal/terminal (URXD0) should meet the timing requirements of t_(T) to ensure that the URXS flip-flop is set. The URXS flip-flop is set with negative pulses meeting the minimum-timing condition of t_(T). The operating conditions to set the flag must be met independently from this timing constraint. The deglitch circuitry is active only on negative transitions on the URXD0 line.

Timer_A3

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f _{TA} Timer_A3 clock frequency	SMCLK, Duty cycle = 50% ± 10%			f _{SYSTEM}		MHz
t _{TA,cap} Timer_A3, capture timing	TA0, TA1	3 V	20			ns

Flash Memory

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
V _{CC(PGM/ERASE)} Program and erase supply voltage			2.2		3.6	V
f _{FTG} Flash timing generator frequency			257		476	kHz
I _{PGM} Supply current from V _{CC} during program		2.2 V/3.6 V		1	5	mA
I _{ERASE} Supply current from V _{CC} during erase		2.2 V/3.6 V		1	7	mA
t _{CPT} Cumulative program time ⁽¹⁾		2.2 V/3.6 V			10	ms
t _{CMErase} Cumulative mass erase time		2.2 V/3.6 V	20			ms
Program/erase endurance			10 ⁴	10 ⁵		cycles
t _{Retention} Data retention duration	T _J = 25°C		100			years
t _{Word} Word or byte program time	⁽²⁾			30		t _{FTG}
t _{Block, 0} Block program time for first byte or word	⁽²⁾			25		t _{FTG}
t _{Block, 1-63} Block program time for each additional byte or word	⁽²⁾			18		t _{FTG}
t _{Block, End} Block program end-sequence wait time	⁽²⁾			6		t _{FTG}
t _{Mass Erase} Mass erase time	⁽²⁾			10593		t _{FTG}
t _{Seg Erase} Segment erase time	⁽²⁾			4819		t _{FTG}

- (1) The cumulative program time must not be exceeded when writing to a 64-byte flash block. This parameter applies to all programming methods: individual word/byte write and block write modes.
- (2) These values are hardwired into the flash controller's state machine (t_{FTG} = 1 / f_{FTG}).

RAM

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT
$V_{(RAMh)}$	RAM retention supply voltage ⁽¹⁾	CPU halted	1.6		V

- (1) This parameter defines the minimum supply voltage V_{CC} when the data in RAM remains unchanged. No program execution should happen during this supply voltage condition.

JTAG and Spy-Bi-Wire Interface

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V_{CC}	MIN	TYP	MAX	UNIT
f_{SBW}	Spy-Bi-Wire input frequency		3 V	0		20	MHz
$t_{SBW,Low}$	Spy-Bi-Wire low clock pulse length		3 V	0.025		15	μ s
$t_{SBW,En}$	Spy-Bi-Wire enable time (TEST high to acceptance of first clock edge ⁽¹⁾)		3 V			1	μ s
$t_{SBW,Ret}$	Spy-Bi-Wire return to normal operation time		3 V	15		100	μ s
f_{TCK}	TCK input frequency ⁽²⁾		3 V	0		10	MHz
$R_{Internal}$	Internal pulldown resistance on TEST		3 V	25	60	90	k Ω

- (1) Tools accessing the Spy-Bi-Wire interface must wait for the maximum $t_{SBW,En}$ time after pulling the TEST/SBWCLK pin high before applying the first SBWCLK clock edge.
(2) f_{TCK} may be restricted to meet the timing requirements of the module selected.

JTAG Fuse⁽¹⁾

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT
$V_{CC(FB)}$	Supply voltage during fuse-blow condition	$T_A = 25^\circ\text{C}$	2.5		V
V_{FB}	Voltage level on TEST for fuse blow		6	7	V
I_{FB}	Supply current into TEST during fuse blow			100	mA
t_{FB}	Time to blow fuse			1	ms

- (1) Once the fuse is blown, no further access to the JTAG/Test, Spy-Bi-Wire, or emulation feature is possible, and JTAG is switched to bypass mode.

APPLICATION INFORMATION

Port P1 Pin Schematic: P1.0 Input/Output With Schmitt Trigger

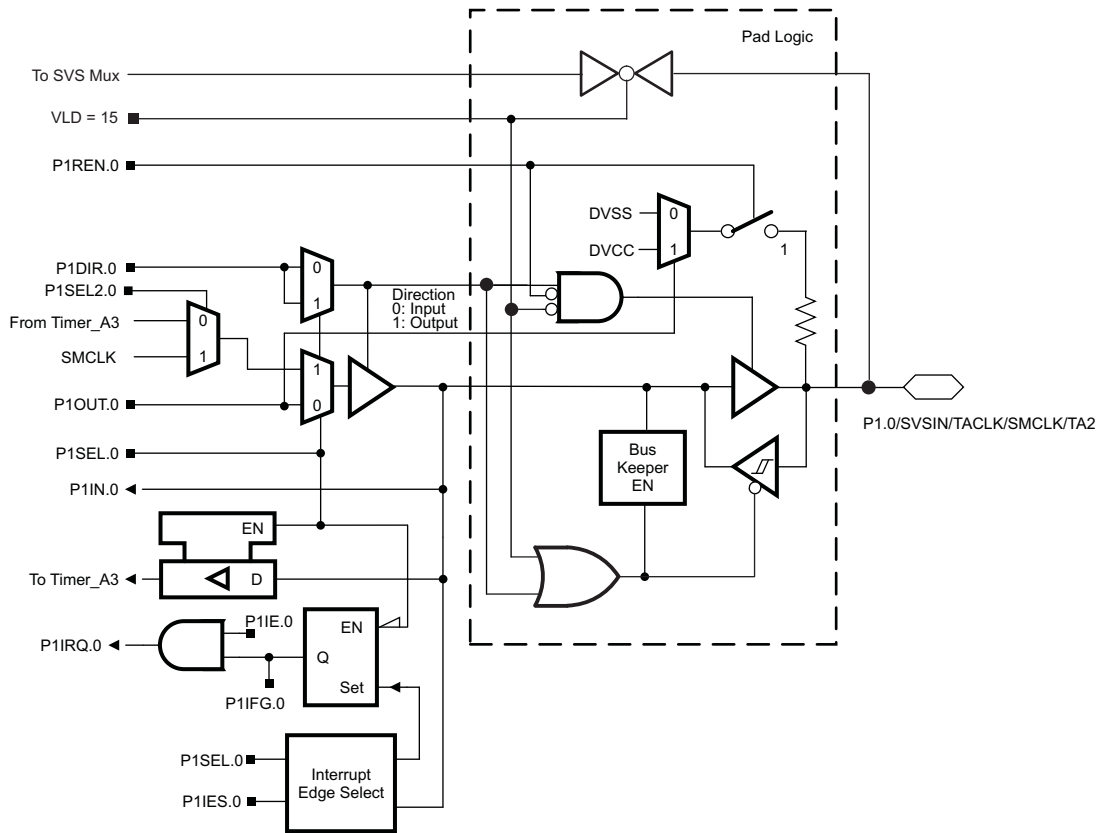


Table 17. Port P1 (P1.0) Pin Functions

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNALS ⁽¹⁾		
			P1DIR.x	P1SEL.x	P1SEL2.x
P1.0/SVSIN/TACLK/SMCLK/TA2	0	P1.0 (I/O)	I: 0, O: 1	0	X
		SVSIN (VLD = 15)	X	X	X
		Timer_A3.TACLK	0	1	0
		SMCLK	1	1	1
		Timer_A3.TA2	1	1	0

(1) X = don't care

Port P1 Pin Schematic: P1.1 and P1.2 Input/Output With Schmitt Trigger

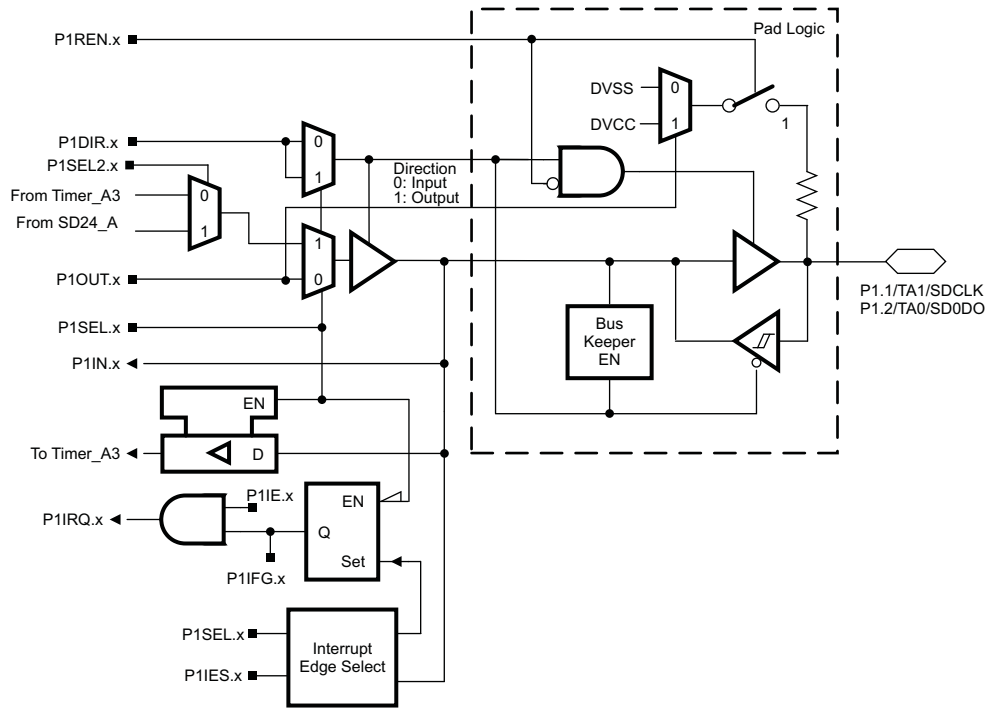


Table 18. Port P1 (P1.1 and P1.2) Pin Functions

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNAL ⁽¹⁾		
			P1DIR.x	P1SEL.x	P1SEL2.x
P1.1/TA1/SDCLK	1	P1.1 (I/O)	I: 0, O: 1	0	X
		Timer_A3.CCI1A and CCI1B	0	1	0
		Timer_A3.TA1	1	1	0
		SDCLK	1	1	1
P1.2/TA0/SD0DO	2	P1.2 (I/O)	I: 0, O: 1	0	X
		Timer_A3.CCI0A and CCI0B	0	1	0
		Timer_A3.TA0	1	1	0
		SD0DO	1	1	1

(1) X = don't care

Port P1 Pin Schematic: P1.3 Input/Output With Schmitt Trigger

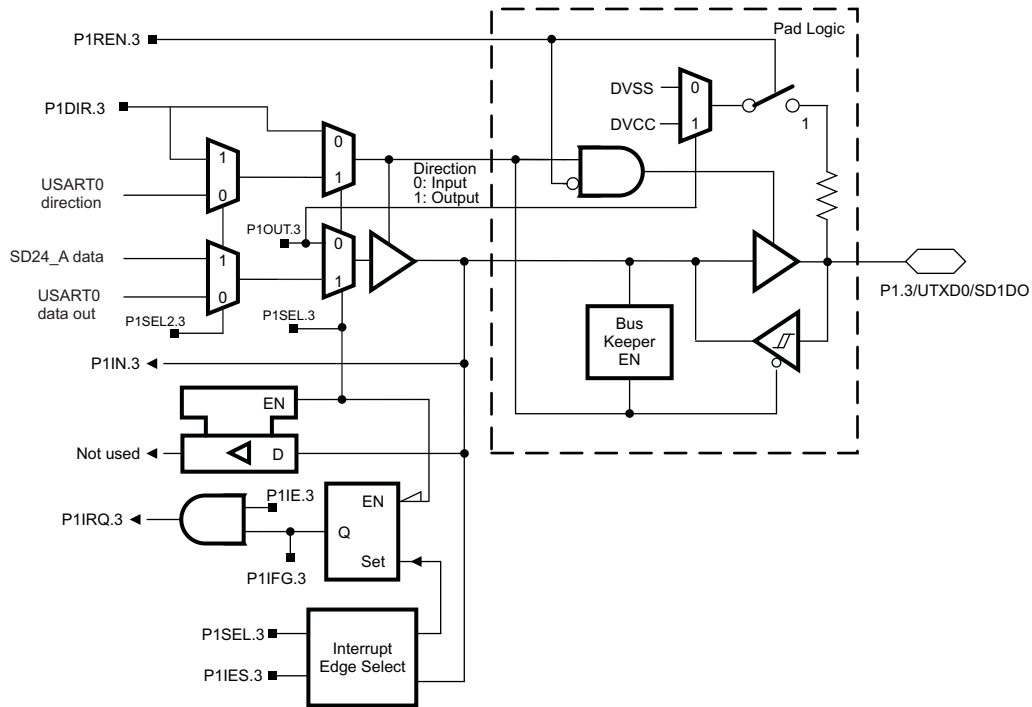


Table 19. Port P1 (P1.3) Pin Functions

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNALS ⁽¹⁾		
			P1DIR.x	P1SEL.x	P1SEL2.x
P1.3/UTXD0/SD1DO	3	P1.3 (I/O)	I: 0, O: 1	0	X
		UTXD0	X	1	0
		SD1DO	1	1	1

(1) X = don't care

Port P1 Pin Schematic: P1.4 Input/Output With Schmitt Trigger

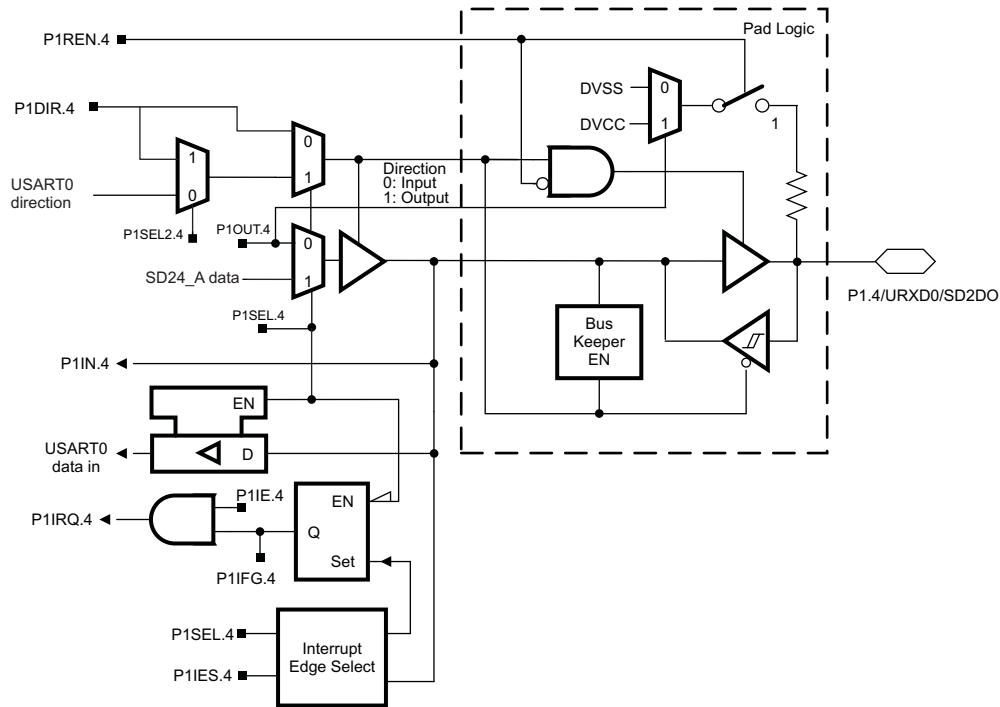


Table 20. Port P1 (P1.4) Pin Functions

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNALS ⁽¹⁾		
			P1DIR.x	P1SEL.x	P1SEL2.x
P1.4/URXD0/SD2DO	4	P1.4 (I/O)	I: 0, O: 1	0	X
		URXD0	X	1	0
		SD2DO	1	1	1

(1) X = don't care

Port P1 Pin Schematic: P1.5 to P1.7 Input/Output With Schmitt Trigger

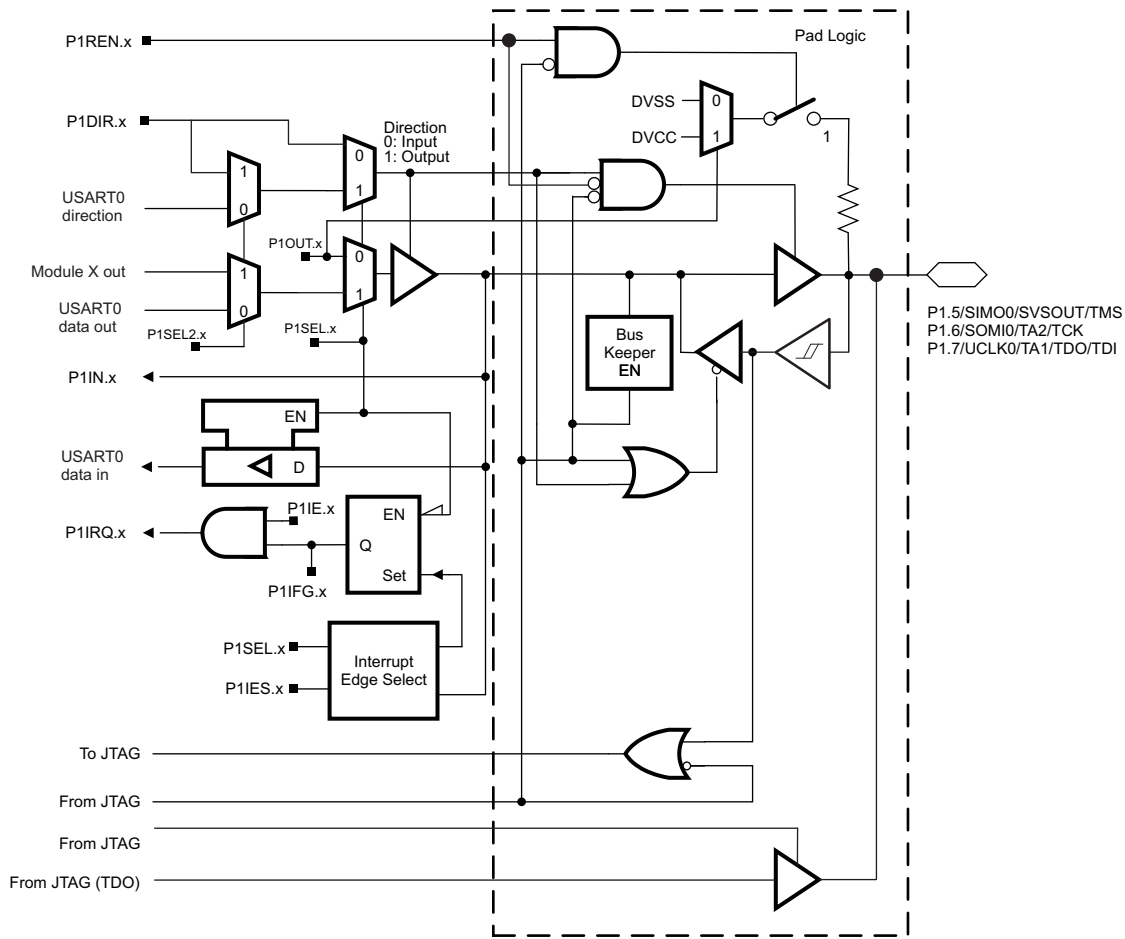


Table 21. Port P1 (P1.5 to P1.7) Pin Functions

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNALS ⁽¹⁾			
			P1DIR.x	P1SEL.x	P1SEL2.x	JTAG Mode ⁽²⁾
P1.5/SIMO0/SVSOUT/TMS	5	P1.5 (I/O)	I: 0; O: 1	0	X	0
		SIMO0	X	1	0	0
		SVSOUT	1	1	1	0
		TMS	X	X	X	1
P1.6/SOMI0/TA2/TCK	6	P1.6 (I/O)	I: 0; O: 1	0	X	0
		SOMI0	X	1	0	0
		Timer_A3.TA2 TCK	1 X	1 X	1 X	0 1
P1.7/UCLK0/TA1/TDO/TDI	7	P1.7 (I/O)	I: 0; O: 1	0	X	0
		UCLK0	X	1	0	0
		Timer_A3.TA1	1	1	1	0
		TDO/TDI	X	X	X	1

(1) X = don't care

(2) JTAG Mode is not a register bit but signal generated internally when 4-wire JTAG option is selected in IDE

Port P2 Pin Schematic: P2.0 Input/Output With Schmitt Trigger

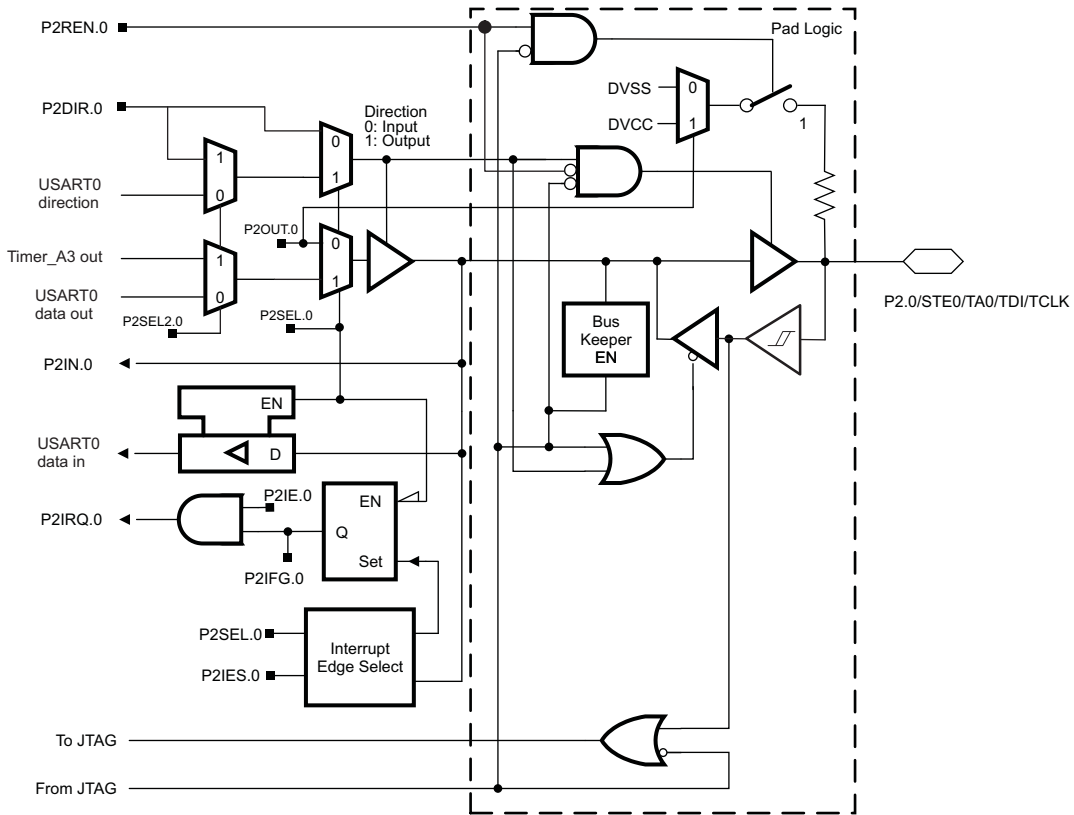


Table 22. Port P2 (P2.0) Pin Functions

PIN NAME (P2.x)	x	FUNCTION	CONTROL BITS / SIGNALS ⁽¹⁾			
			P2DIR.x	P2SEL.x	P2SEL2.x	JTAG Mode ⁽²⁾
P2.0/STE0/TA0/TDI/TCLK	0	P2.0 (I/O)	I: 0; O: 1	0	X	0
		STE0	X	1	0	0
		Timer_A3.TA0	1	1	1	0
		TDI/TCLK	X	X	X	1

(1) X = don't care

(2) JTAG Mode is not a register bit but signal generated internally when 4-wire JTAG option is selected in IDE

Port P2 Pin Schematic: P2.6, Input/Output With Schmitt Trigger

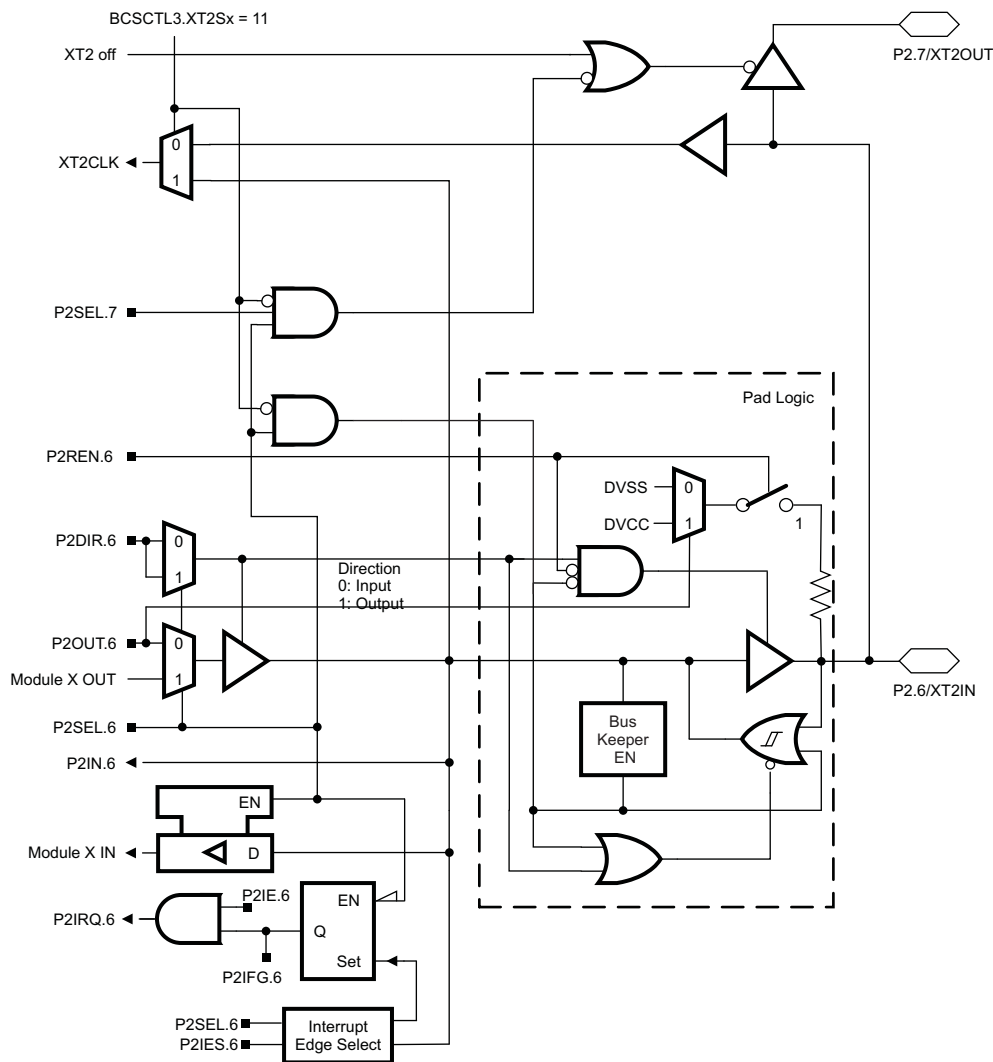


Table 23. Port P2 (P2.6) Pin Functions

Pin Name (P2.x)	x	FUNCTION	CONTROL BITS / SIGNALS	
			P2DIR.6	P2SEL.6
P2.6/XT2IN	6	P2.6 (I/O)	I: 0; O: 1	0
		XT2IN (default)	0	1

Port P2 Pin Schematic: P2.7, Input/Output With Schmitt Trigger

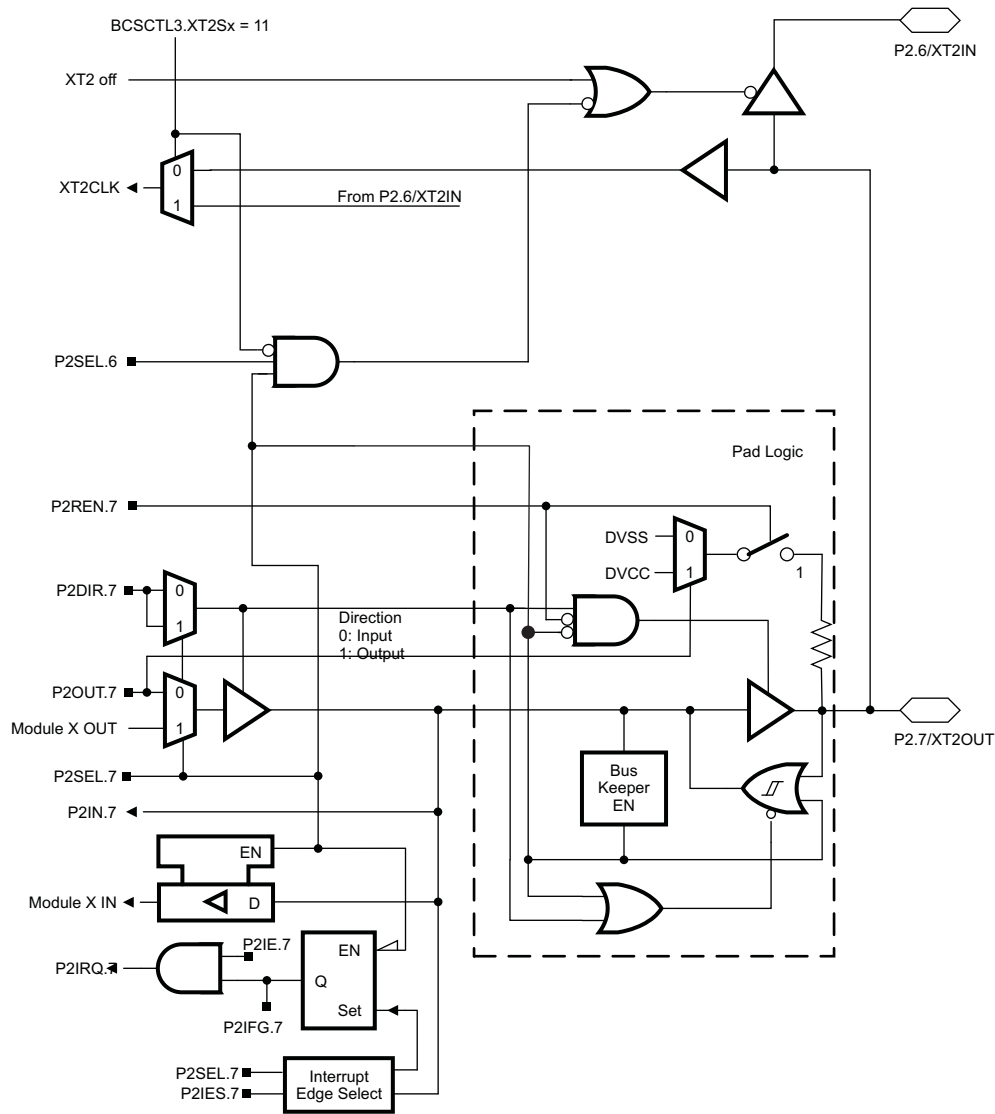


Table 24. Port P2 (P2.7) Pin Functions

PIN NAME (P2.x)	x	FUNCTION	CONTROL BITS / SIGNALS	
			P2DIR.7	P2SEL.7
P2.7/XT2OUT	7	P2.7 (I/O)	I: 0, O: 1	0
		XT2OUT (default)	0	1

JTAG Fuse Check Mode

MSP430 devices that have the fuse on the TEST terminal have a fuse check mode that tests the continuity of the fuse the first time the JTAG port is accessed after a power-on reset (POR). When activated, a fuse check current, I_{TF} , of 1 mA at 3 V or 2.5 mA at 5 V can flow from the TEST pin to ground if the fuse is not burned. Care must be taken to avoid accidentally activating the fuse check mode and increasing overall system power consumption.

When the TEST pin is again taken low after a test or programming session, the fuse check mode and sense currents are terminated.

Activation of the fuse check mode occurs with the first negative edge on the TMS pin after power up or if TMS is being held low during power up. The second positive edge on the TMS pin deactivates the fuse check mode. After deactivation, the fuse check mode remains inactive until another POR occurs. After each POR, the fuse check mode has the potential to be activated.

The fuse check current flow only when the fuse check mode is active and the TMS pin is in a low state (see [Figure 17](#)). Therefore, the additional current flow can be prevented by holding the TMS pin high (default condition).

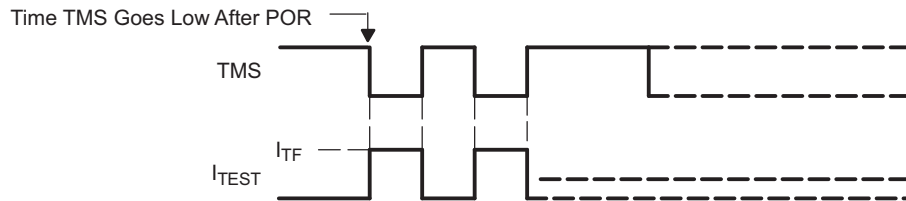


Figure 17. Fuse Check Mode Current

NOTE

The CODE and RAM data protection is ensured if the JTAG fuse is blown.

REVISION HISTORY

REVISION	COMMENTS
SLAS701	Product Preview release
SLAS701A	Production Data release

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/ Ball Finish	MSL Peak Temp ⁽³⁾	Samples (Requires Login)
MSP430AFE221IPW	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE221IPWR	ACTIVE	TSSOP	PW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE222IPW	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE222IPWR	ACTIVE	TSSOP	PW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE223IPW	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE223IPWR	ACTIVE	TSSOP	PW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE231IPW	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE231IPWR	ACTIVE	TSSOP	PW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE232IPW	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE232IPWR	ACTIVE	TSSOP	PW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE233IPW	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE233IPWR	ACTIVE	TSSOP	PW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE251IPW	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE251IPWR	ACTIVE	TSSOP	PW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE252IPW	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE252IPWR	ACTIVE	TSSOP	PW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
MSP430AFE253IPW	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/ Ball Finish	MSL Peak Temp ⁽³⁾	Samples (Requires Login)
MSP430AFE253IPWR	ACTIVE	TSSOP	PW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
XMS430AFE253IPWR	OBSOLETE	TSSOP	PW	24		TBD	Call TI	Call TI	

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

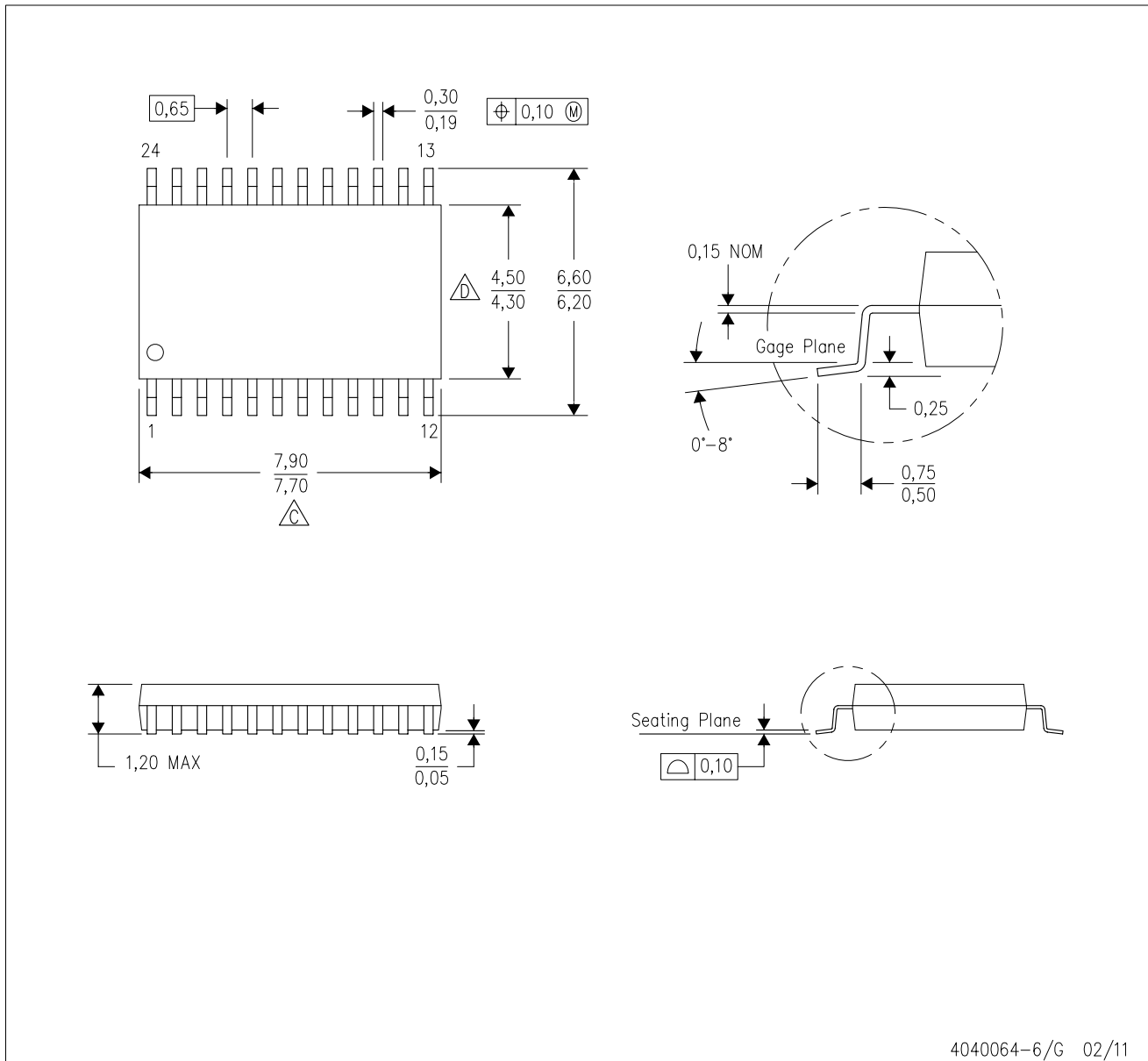
⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.



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PW (R-PDSO-G24)

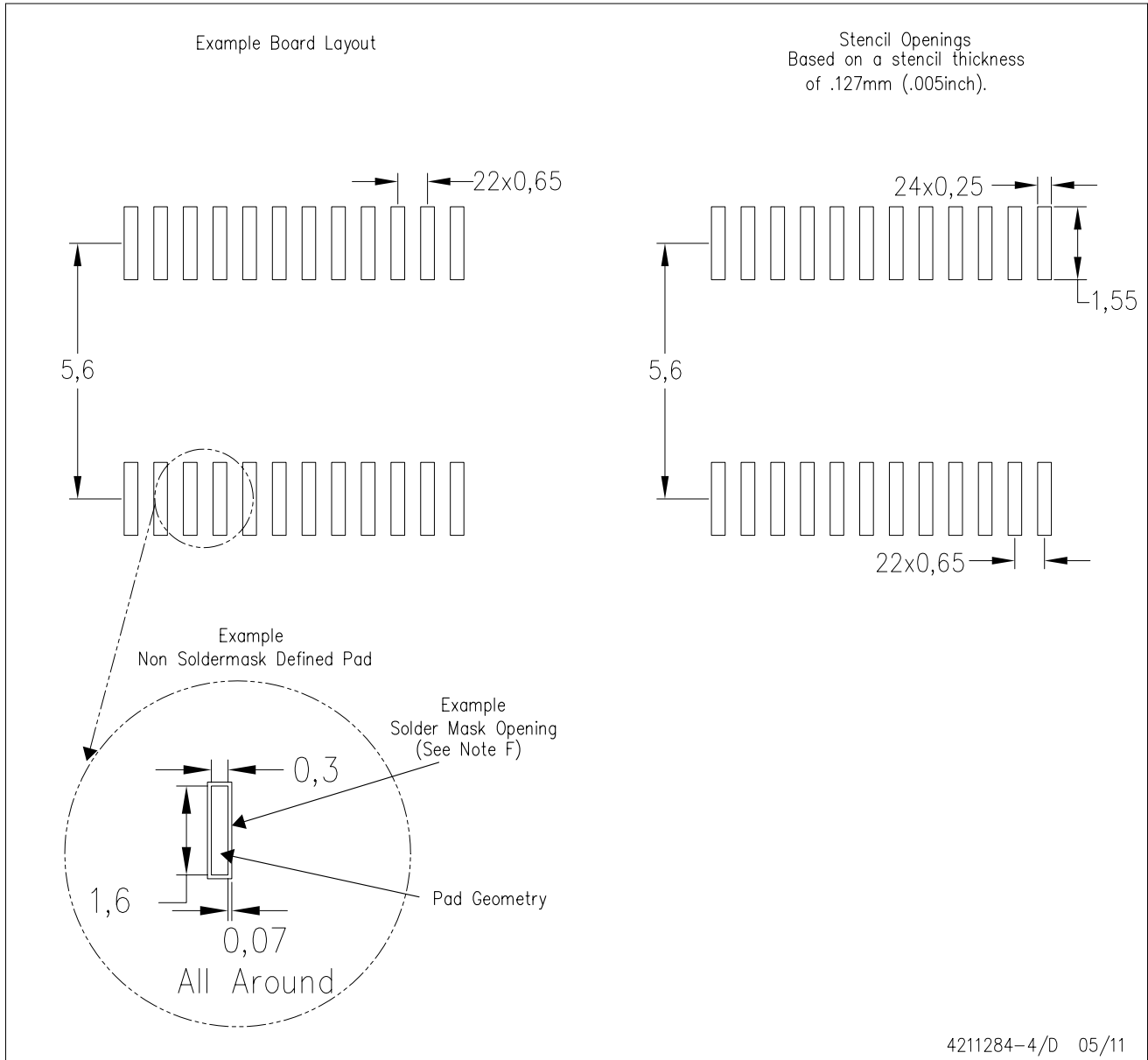
PLASTIC SMALL OUTLINE



- NOTES:
- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 - B. This drawing is subject to change without notice.
 -  Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
 -  Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
 - E. Falls within JEDEC MO-153

PW (R-PDSO-G24)

PLASTIC SMALL OUTLINE



- NOTES:
- All linear dimensions are in millimeters.
 - This drawing is subject to change without notice.
 - Publication IPC-7351 is recommended for alternate design.
 - Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
 - Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

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